

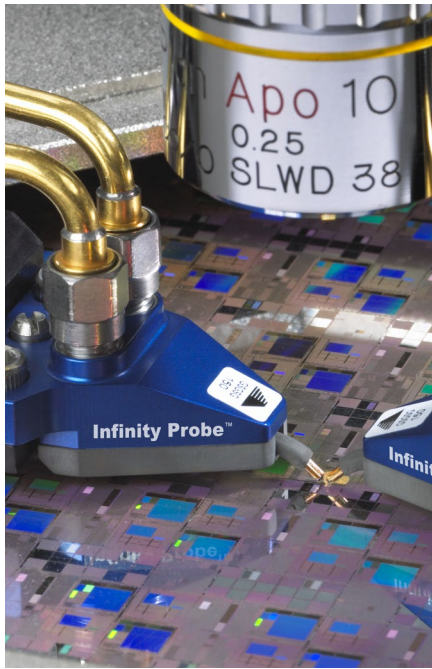


Probe Selection Guide

More than 50 different probing solutions for wafer, package, and board-level characterization.

Cascade Microtech offers a wide selection of engineering probes to meet the highly demanding and broad range of on-wafer and signal integrity applications. Our families of RF, mixed-signal and DC probes are designed to meet the many challenges of the various probing environments and provide a durable, high-performance product that exceeds expectations.

TABLE OF CONTENTS



| | |
|--|--------------------|
| Probe family overview | 3 |
| Quick probe selection guides | |
| Probe Selection Guide: RF Probes | 5 |
| Probe Selection Guide: Waveguide Probe Guide | 6 |
| Probe Selection Guide: Mixed-Signal Probes | 7 |
| Probe Selection Guide: DC Multi-Contact Probes | 8 |
| Single and dual RF/microwave probes (coaxial and waveguide) | |
| Infinity Probes® – coaxial | 10 |
| Infinity Probes – waveguide | 12 |
| T-Wave™ Probe | 14 |
| Air Coplanar Probes® (ACP) – coaxial and waveguide | 17 |
| Z Probes® | 20 |
| RFIC and functional test (multi-contact) probes | |
| Multi-contact RF probes | |
| InfinityQuad™ probes | 21 |
| Unity Probes™ | 22 |
| ACP quadrant probes | 23 |
| Z Probes | 24 |
| Multi-contact DC probes | |
| Eye-Pass® probes | 25 |
| DCQ probes | 26 |
| WPH probes | 26 |
| Board test and signal integrity probes | |
| Fixed-pitch compliant probes (FPC) | 27 |
| Special-purpose RF/microwave probes | |
| Impedance matching probes | 28 |
| High-performance quadrant probes | 29 |
| Cryogenic probes | 29 |
| Supporting accessories | |
| Impedance standard substrates (ISS) | 30 |
| Cables | 31 |
| WinCal XE™ RF calibration software | 32 |

PROBE FAMILY OVERVIEW

Cascade Microtech offers a wide selection of engineering probes to meet the highly demanding and broad range of on-wafer and signal integrity applications. Our families of RF, mixed-signal and DC probes are designed to meet the many challenges of the various probing environments and provide a durable, high-performance product that exceeds expectations.



Infinity Probes

The Infinity Probe is an ideal match for device characterization and modeling and differential applications, with industry-leading performance. The Infinity Probe provides unmatched performance in both single-signal and dual-signal (differential) applications, providing extremely low contact resistance on aluminum pads with unsurpassed RF measurement accuracy for highly reliable, repeatable measurements. The Infinity Probe is designed for on-wafer/planar surface work only. Proprietary thin-film and coaxial probe technology reduces unwanted couplings to nearby devices and transmission modes. [\[page 10\]](#)



T-Wave Probes

The T-Wave Probes enable wafer-level electrical measurement of millimeterwave devices and materials up to 1.1 THz, setting the industry performance standard for characterization of millimeter and sub-millimeter wavelength devices. The T-Wave Probes deliver low insertion loss and low contact resistance when probing gold pads. [\[page 14\]](#)



Air Coplanar Probes

The Air Coplanar Probe (ACP) is a rugged microwave probe with a compliant tip for accurate, repeatable measurements for both on-wafer as well signal integrity applications. It features excellent probe-tip visibility and the lowest loss available. Configurations for both single and dual signal applications are available. The ACP probe combines outstanding electrical performance with precise probe mechanics and is today's most widely used microwave probe available. [\[page 17\]](#)



|Z| Probes

The |Z| Probes assure long probe lifetime and accurate measurements with superior tip compliance. The RF/Microwave signal makes only one transition to the coplanar contact structure within the shielded, air-isolated probe body maintaining signal integrity over a temperature range from 10 K to 300°C. [\[page 20\]](#)



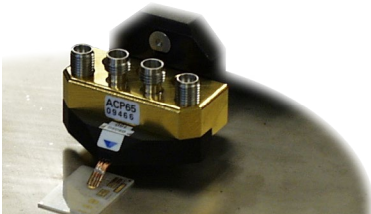
RFIC and Functional Test (multi-contact) Probes

Cascade Microtech offers a variety of durable, high-performance mixed-signal multi-contact probes to streamline RFIC engineering test and production applications up to 110 GHz. The multi-contact probe families include InfinityQuad probe, Multi |Z| Probe, Unity Probe, ACP RF quadrant probe, Eye-Pass probe, DCQ and WPH probes. [\[page 21\]](#)



Board Test and Signal Integrity Probes

Cascade Microtech offers precision, durable fine-pitch probes, ideal for signal integrity probing on IC packages and circuit board work. Many of these probes allow for deep reach capabilities to access contacts over adjacent components. Probes are available to meet the performance requirements of both circuit work or material characterization. [\[page 27\]](#)



Special-purpose RF/microwave Probes

Cascade Microtech offers many custom probes, so if an exact match is not found in this guide, please contact us for a review to determine if we have a probe that will fit your requirements or if we can customize a probe to fit your application.

Some example applications/probes are [\[page 28\]](#):

- Impedance matching probe
- High-performance quadrant probe
- Cryogenic probe

The estimated lifetime indicated in this document can be negatively affected by several variables, such as overtravel used, planarity of the substrate, materials being probed, debris on the surface, skating into passivation, temperature, cleaning frequency and cleaning media.

QUICK PROBE SELECTION GUIDE: RF PROBES

| Key Specifications | | | Z Probes | | Infinity | | ACP | |
|---|---------------------------------------|------------------------|------------|----------------------|------------|-------------------------|------------|----------------|
| | | | Single | Dual | Single | Dual | Single | Dual |
| Maximum Frequency | | 67 GHz | 50 GHz | 110 GHz | 110 GHz | 110 GHz | 110 GHz | |
| Minimum Pad Size | | 50x50 μm | 50x50 μm | 25x35 μm | 25x35 μm | 80x80 μm | 80x80 μm | |
| Typical Raw Insertion Loss @ 40 GHz | | 0.8 dB | 0.8 dB | 0.7 dB | 0.9 dB | 1.0/0.6 dB ³ | 1.25 dB | |
| Compliance | | 50/300 μm ¹ | 50 μm | 1 μm | 1 μm | 25 μm | 25 μm | |
| Standard Pitch Range | | 50-1250 μm | 100-500 μm | 50-250 μm | 100-250 μm | 100-1250 μm | 100-500 μm | |
| Maximum DC Current | | 1.5 A | 1.5 A | 0.5/2 A ⁴ | 0.5 A | 5 A | 5 A | |
| Maximum RF Power @ 2 GHz | | 15/65 W ² | 15 W | 37 dBm | 37 dBm | 30 W | 30 W | |
| Typical Lifetime on Al Pads | | >1,000,000 | >1,000,000 | >250,000 | >250,000 | >500,000 | >500,000 | |
| Maximum Temperature | | 300°C | 200°C | 125°C | 125°C | 200°C | 200°C | |
| Typical Contact Resistance on Al | | 50 mΩ | 50 mΩ | 30 mΩ | 30 mΩ | 100 mΩ | 100 mΩ | |
| Device Modeling and Characterization - Si | 2-Port S-Parameter Measurements | DC-67 GHz | ● | | ● | | ○ | |
| | | 67-110 GHz | | | ● | | ○ | |
| | Differential S-Parameter Measurements | DC-67 GHz | | ● | | ● | | ○ |
| | | 67-110 GHz | | | | ● | | ○ |
| | Load-Pull Measurements | DC-67 GHz | ● | | ● | | ○ | |
| | | 67-110 GHz | | | ● | | ○ | |
| Device Modeling and Characterization - GaAs | 2-Port S-Parameter Measurements | DC-67 GHz | ● | | ● | | ● | |
| | | 67-110 GHz | | | ● | | ● | |
| | Differential S-Parameter Measurements | DC-67 GHz | | ● | | ● | | ● |
| | | 67-110 GHz | | | | ● | | ● |
| | Load-Pull Measurements | DC-67 GHz | ● | | ● | | ● | |
| | | 67-110 GHz | | | ● | | ● | |
| Production Testing - RF Discrete Devices | Al Pads | DC-67 GHz | ● | For multi-port | ● | ● | | |
| | | 67-110 GHz | | | ● | For multi-port | | |
| | Au Pads | DC-67 GHz | ● | For multi-port | ○ | ○ | ● | ● |
| | | 67-110 GHz | | | ○ | ○ | ● | For multi-port |
| PCB Board Test** | Single Signal | DC-67 GHz | ● | | | | ● | |
| | | 67-110 GHz | | | | | ● | |
| | Multi-port/Differential | DC-67 GHz | | ● | | | | ● |
| | | 67-110 GHz | | | | | | ● |

¹ For |Z| Probe PCB
² For high-power |Z| Probe
³ For low-loss ACP probe
⁴ For high-current Infinity Probe
 * T-Wave probes available from 220 GHz to 1.1 THz.
 ** Infinity probes available up to 500 GHz.

QUICK PROBE SELECTION GUIDE: WAVEGUIDE PROBE GUIDE

| | | Key Specifications | | |
|---------------------------------------|------------------------------|----------------------|----------------------|-----------------------|
| | | T-Wave | Infinity | ACP |
| Maximum Frequency | | 1.1 THz | 500 GHz | 140 GHz |
| Minimum Pad Size | | 25x35 μm | 25x35 μm | 25x35 μm |
| Compliance | | 1 μm | 1 μm | 25 μm |
| Standard Pitch Range | | 25-100 μm | 50-150 μm | 100-250 μm |
| Typical Lifetime on Al Pads | | NS | >250,000 | >500,000 |
| Maximum Temperature | | 125°C | 125°C | 200°C |
| Typical Contact Resistance on Al | | 300 m Ω | 30 m Ω | 100 m Ω |
| Device Modelling and Characterization | Al Pads | | | |
| | Au Pads | | | |
| Product Testing - RF Discrete Devices | Al Pads | | | |
| | Au Pads | | | |
| PCB Board Test | Single Signal | NR | NR | |
| Available Waveguide Bands | WR - 15 (50 GHz - 75 GHz) | | ✓ | ✓ |
| | WR - 12 (60 GHz - 90 GHz) | | ✓ | ✓ |
| | WR - 10 (75 GHz - 110 GHz) | | ✓ | ✓ |
| | WR - 8 (90 GHz - 140 GHz) | | ✓ | ✓ |
| | WR - 6 (110 GHz - 170 GHz) | | ✓ | |
| | WR - 5 (140 GHz - 220 GHz) | ✓ | ✓ | |
| | WR - 4 (170 GHz - 260 GHz) | ✓ | ✓* | |
| | WR - 3 (220 GHz - 325 GHz) | ✓ | ✓ | |
| | WR - 2 (325 GHz - 500 GHz) | ✓ | ✓ | |
| | WR - 1.5 (500 GHz - 750 GHz) | ✓ | | |
| | WR - 1 (750 GHz - 1.1 THz) | ✓ | | |

* Available upon request

= Best (Recommended) = Good = Acceptable NR = Not Recommended

QUICK PROBE SELECTION GUIDE: MIXED-SIGNAL / MULTI-CONTACT PROBES

| | | | Key Specifications | | | | | |
|------------------------|---|-------------------|---------------------------|----------|----------|----------|------------------------------|----|
| | | | InfinityQuad | Multi Z | Unity | ACP-Q | Z Probe HF ProbeWedge™ | |
| | | | 25 | 35 | 12 | 16 | 12 | |
| | | | 110 GHz | 20 GHz | 20 GHz | 110 GHz | 67 GHz | |
| | | | 25 | 16 | 8 | 3 | 2 | |
| | | | 30x50 μm | 60x60 μm | 95x95 μm | 80x80 μm | 80x80 μm | |
| | | | Eye-Pass | On-board | Eye-Pass | On-Tip | On-Tip | |
| | | | No | Yes | No | Yes | Yes | |
| | | | 125°C | 200°C | 125°C | 125°C | 125°C | |
| | | | Yes | No | Yes | No | No | |
| IC Test Engineering | Characterization and Verification | Uniform Pitch | <20 GHz | ● | ● | ● | ○ | ○ |
| | | | >20 GHz | ● | NR | NR | ○ | ○ |
| | | Non-Uniform Pitch | <20 GHz | NR | ● | NR | ● | ● |
| | | | >20 GHz | NR | NR | NR | ● | ● |
| | Failure Analysis and Design Debug | Uniform Pitch | <20 GHz | ● | ● | ● | ○ | ○ |
| | | | >20 GHz | ● | NR | NR | ○ | ○ |
| | Non-Uniform Pitch | <20 GHz | NR | ● | NR | ● | ● | |
| | | >20 GHz | NR | NR | NR | ● | ● | |
| Production Test | Pre-Production | Uniform Pitch | <20 GHz | ● | ● | ● | ○ | ○ |
| | | | >20 GHz | ● | NR | NR | ○ | ○ |
| | | Non-Uniform Pitch | <20 GHz | NR | ● | NR | ● | ● |
| | | | >20 GHz | NR | NR | NR | ● | ● |
| | Small Scale Production | Uniform Pitch | <20 GHz | ● | ● | ● | ○ | ○ |
| | | | >20 GHz | ● | NR | NR | ○ | ○ |
| | | Non-Uniform Pitch | <20 GHz | NR | ● | NR | ● | ● |
| | | | >20 GHz | NR | NR | NR | ● | ● |
| | Large Scale Production | Uniform Pitch | <20 GHz | ● | ● | ● | ○ | ○ |
| | | | >20 GHz | ● | NR | NR | ○ | ○ |
| | | Non-Uniform Pitch | <20 GHz | NR | ● | NR | ● | ● |
| | | | >20 GHz | NR | NR | NR | ● | ● |
| Application Specific | Small Pads and Scribe-Street Devices | Uniform Pitch | <20 GHz | ● | ○ | NR | NR | NR |
| | | | >20 GHz | ● | NR | NR | NR | NR |
| | | Non-Uniform Pitch | <20 GHz | NR | ○ | NR | NR | NR |
| | | | >20 GHz | NR | NR | NR | NR | NR |
| | mm-Wave Complex IC test (Wireless HDMI, Automobile Radar) | Uniform Pitch | — | ● | NR | NR | ● | NR |
| | | Non-Uniform Pitch | — | NR | NR | NR | Recommend uniform pitch pads | NR |
| | PCB Board Test | Uniform Pitch | <20 GHz | NR | ● | ○ | ● | ● |
| | | | >20 GHz | NR | NR | NR | ● | ● |
| | | Non-Uniform Pitch | <20 GHz | NR | ● | NR | ● | ● |
| | | | >20 GHz | NR | NR | NR | ● | ● |
| Package Device Probing | Uniform Pitch | <20 GHz | NR | ● | ○ | ● | ● | |
| | | >20 GHz | NR | NR | NR | ● | ● | |
| | Non-Uniform Pitch | <20 GHz | NR | ● | NR | ● | ● | |
| | | >20 GHz | NR | NR | NR | ● | ● | |

● = Best (Recommended) ● = Good ○ = Acceptable NR = Not Recommended

QUICK PROBE SELECTION GUIDE: DC MULTI-CONTACT PROBES

| Key Specifications | Eye-Pass | DCQ | WPH-900 | Multi Z | ProbeWedge WE | ProbeWedge WD |
|------------------------------|---------------------|---------------------|---------------------|---------------------|---------------------|---------------------|
| Maximum Number Contacts | 12 | 16 | 12 | 35 | 16 | 40 |
| Power De-coupling | Eye-Pass | On tip blade | On tip blade | On-board | On tip blade | On-board |
| Maximum Current | 1 A | 500 mA | 500 mA | 1 A | 100 mA | 100 mA |
| Maximum Voltage | 50 V | 50 V | 50 V | 100 V | 50 V | 50 V |
| RF Bandwidth | 500 MHz | 500 MHz | 500 MHz | 500 MHz | 500 MHz | 50 MHz |
| Typical Lifetime on Al Pads | >250,000 | >250,000 | >250,000 | >1,000,000 | >250,000 | >250,000 |
| Recommended Minimum Pad Size | 95x95 μm | 50x50 μm | 50x50 μm | 60x60 μm | 80x80 μm | 80x80 μm |
| Non-Uniform Pitch | No | Yes | Yes | Yes | Yes | Yes |
| Maximum Temperature | 125°C | 125°C | 125°C | 200°C | 125°C | 125°C |
| Online Design Capture | Yes | No | No | No | No | No |

| IC Test Engineering | Application | Pitch | Contacts | Eye-Pass | DCQ | WPH-900 | Multi Z | ProbeWedge WE | ProbeWedge WD |
|-----------------------------------|-----------------------------------|-------------------|--------------|----------|-----|---------|----------|---------------|---------------|
| | | | | Eye-Pass | DCQ | WPH-900 | Multi Z | ProbeWedge WE | ProbeWedge WD |
| IC Test Engineering | Simple IC Bias and Control | Uniform Pitch | <16 contacts | ● | ● | ● | ● | ● | ● |
| | | | >16 contacts | NR | NR | NR | ● | NR | ● |
| | | Non-Uniform Pitch | <16 contacts | NR | ● | ● | ● | ● | ● |
| | | | >16 contacts | NR | NR | NR | ● | NR | ● |
| | Characterization and Verification | Uniform Pitch | <16 contacts | ● | ● | ● | ● | ● | ○ |
| | | | >16 contacts | NR | NR | NR | ● | NR | ● |
| | | Non-Uniform Pitch | <16 contacts | NR | ● | ● | ● | ● | ○ |
| | | | >16 contacts | NR | NR | NR | ● | NR | ● |
| Failure Analysis and Design Debug | Uniform Pitch | <16 contacts | ● | ● | ● | ● | ● | ○ | |
| | | >16 contacts | NR | NR | NR | ● | NR | ● | |
| | Non-Uniform Pitch | <16 contacts | NR | ● | ● | ● | ● | ○ | |
| | | >16 contacts | NR | NR | NR | ● | NR | ● | |
| Production Test | Pre-Production | Uniform Pitch | <16 contacts | ● | ● | ● | ● | ● | ○ |
| | | | >16 contacts | NR | NR | NR | ● | NR | ● |
| | | Non-Uniform Pitch | <16 contacts | NR | ● | ● | ● | ● | ○ |
| | | | >16 contacts | NR | NR | NR | ● | NR | ● |
| | Small Scale Production | Uniform Pitch | <16 contacts | ● | ● | ● | ● | ● | ○ |
| | | | >16 contacts | NR | NR | NR | ● | NR | ● |
| | | Non-Uniform Pitch | <16 contacts | NR | ● | ● | ● | ● | ○ |
| | | | >16 contacts | NR | NR | NR | ● | NR | ● |
| | Large Scale Production | Uniform Pitch | <16 contacts | ● | ● | ● | ● | ● | ○ |
| | | | >16 contacts | NR | NR | NR | ● | NR | ● |
| | | Non-Uniform Pitch | <16 contacts | NR | ● | ● | ● | ● | ○ |
| | | | >16 contacts | NR | NR | NR | ● | NR | ● |

● = Best (Recommended) ● = Good ○ = Acceptable NR = Not Recommended

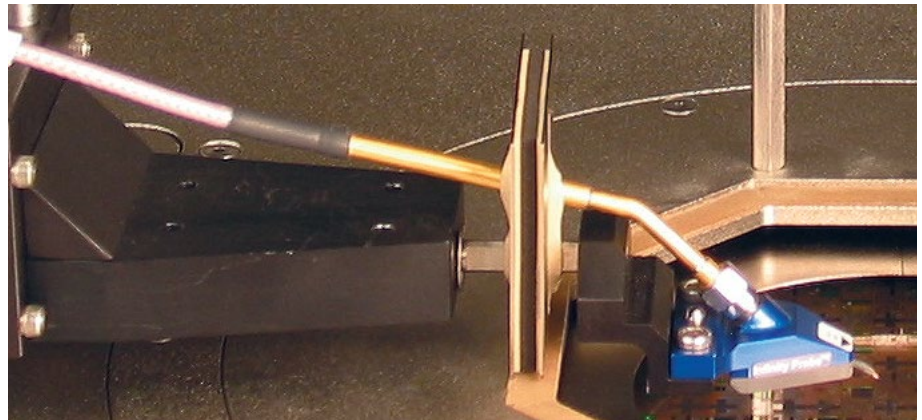
QUICK SELECTION GUIDE: FREQUENCY RANGE AND PERFORMANCE

The best case or maximum frequency range achievable for any given probe is determined by its connector and cable types. Beyond this, the probe tip configuration and pitch are other primary attributes that further limit the usable frequency range. Note that single coaxial probes achieve the best RF performance with a GSG tip configuration and a tip pitch from 75 μm to 250 μm . Above 50 GHz, the optimum performance is achieved with a tip pitch from 100 μm to 150 μm . For dual coaxial probes, the optimum tip configuration is GSGSG and the same probe tip pitch ranges. Cascade Microtech recommends that consideration be given to testability when laying out the pad locations to attain optimum performance.

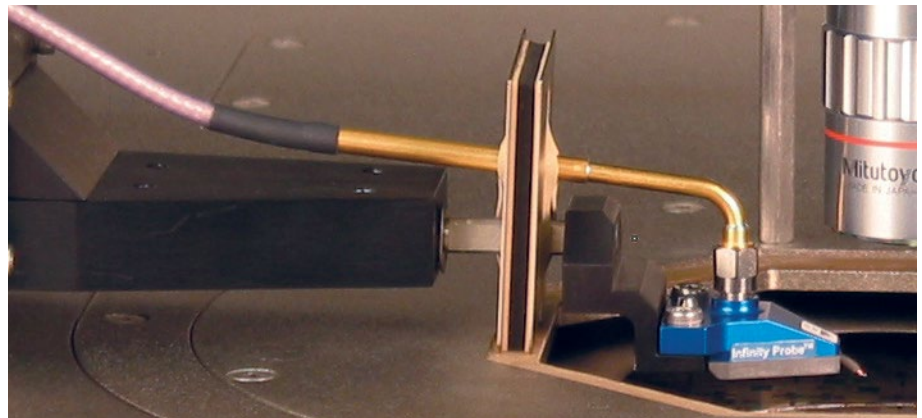
| Connector (Max. frequency) | Probe Body Style | Probe |
|--|-----------------------------|-----------------------------|
| Gore 100 (20 GHz) | Unity probe | Unity Probe |
| 2.92 mm/K(40 GHz) Compatible with SMA (20 GHz), 3.5 mm (26 GHz) | Vertical | I40 / ACP40 |
| | Angled | I40-A / ACP40-A / Z Probe |
| 2.4 mm (50 GHz) | Vertical | I50 / ACP50 |
| | Angled and Low-loss version | I50-A / ACP50-A / Z Probe |
| 1.85 mm (67 GHz) | Vertical | I67 / ACP65 |
| | Angled and Low-loss version | I67-A / ACP65-A / Z Probe |
| 1.0 mm (110 GHz) | Vertical | I110 / ACP110 |
| | Angled | I110-A / ACP110- A |

Notes:

1. Cascade Microtech probes use the 2.92 mm / K connector which is compatible with SMA and 3.5 mm, however it is recommended to use a 2.92 mm cable if possible.
2. ACQ probes use the corresponding connector and cable to match your frequency requirements, e.g., ACP50-Q-xxx uses a RF probe with a 2.4 mm connector.
3. All probe RF connectors are female.



Angled probe body style



Vertical probe body style

INFINITY PROBES



Infinity Probe sets the benchmark for the device characterization and modeling community

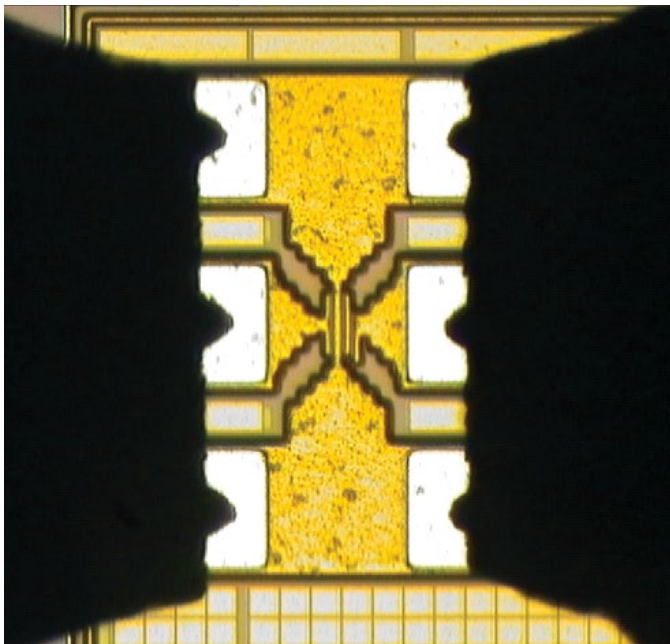
The Infinity probe is truly unique in its architecture that delivers industry leading performance. This revolutionary probe combines extremely low contact resistance on aluminum pads with unsurpassed RF measurement accuracy to provide highly reliable, repeatable measurements. The Infinity Probe reaches this new performance level through the combination of Cascade Microtech's proprietary thin-film technology and coaxial probe technology.

Features

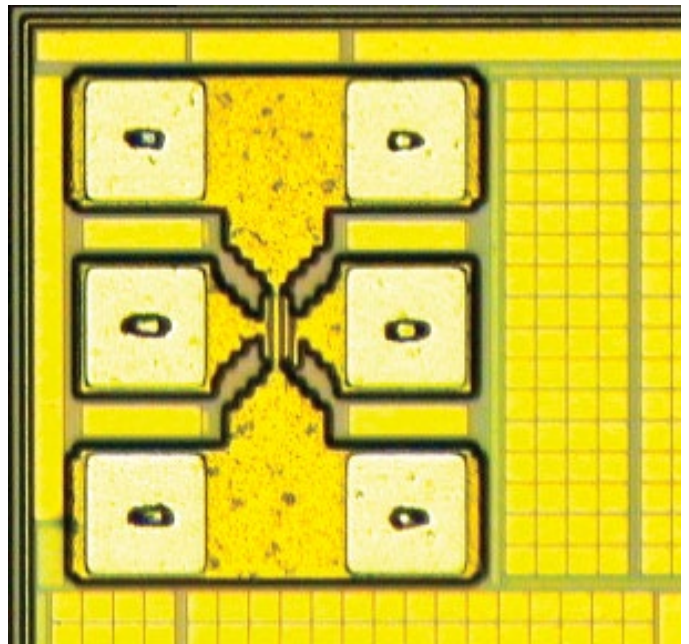
- Lithographic thin-film construction
- Excellent crosstalk characteristics
- Non-oxidizing nickel alloy tips
- Innovative force delivery mechanism
- 40 to 500 GHz versions
- GSG, SG/GS, GSGSG, GSSG, SGS configurations
- Probe pitch as narrow as 50 μm
- High-current version (2 A) available
- Typical lifetime > 250,000 touchdowns on Al pads

Advantages

- Superior field confinement reduces unwanted couplings to nearby devices and transmission modes
- Low, Stable contact resistance
- Superior measurement accuracy and repeatability
- Small scrub minimizes damage to aluminum pad
- Typical contact resistance: < 0.05 Ω on Al, < 0.02 Ω on Au
- Save valuable wafer space and reduce pad parasitics by being able to shrink pad geometries to 25 x 35 μm (best case)
- Reduction in modeling and design cycle time



Infinity Probe contacting Silicon RF device



Small contact marks enable contact to small pads

INFINITY PROBES

| Contact configuration | GSG, SG, GS | Connector | GSGSG, GSSG, SGS |
|---|--|---|--|
| Frequency range for coaxial probes | I40 – DC to 40 GHz I50 – DC to 50 GHz I67 – DC to 67 GHz I110 – DC to 110 GHz (GSG) | I40 - 2.92 mm (f) I50 - 2.4 mm (f) I67 - 1.85 mm (f) I110 - 1 mm (f) | I40 I50 I67 I110 |
| Typical insertion loss (GSG, GSGSG versions only) | | | |
| DC to 40 GHz | 0.7 dB | | 0.9 dB |
| 40 to 50 GHz | 0.8 dB | | 0.9 dB |
| 50 to 67 GHz | 1.1 dB | | 1.2 dB |
| 67 to 110 GHz | 1.4 dB | | 1.6 dB |
| Typical return loss (GSG, GSGSG versions only) | | | |
| DC to 40 GHz | 20 dB | | 15 dB |
| 40 to 50 GHz | 17 dB | | 15 dB |
| 50 to 67 GHz | 16 dB | | 13 dB |
| 67 to 110 GHz | 14 dB | | 11 dB |
| Crosstalk | -50 dB @ 50 GHz | | Typically -40 dB @ 40 GHz; GSGSG 150 Typically -25 dB @ 40 GHz ; GSSG 150 |
| Electrical repeatability | -60 dB | | -60 dB |
| Probe pitch (25 µm increments) | 50 to 250 µm pitch (i40, i50 and i67) 50 to 150 µm pitch (i110) | | 100 to 250 µm pitch - |
| Recommended overtravel | 75 µm | | 75 µm |
| Maximum safe overtravel | 150 µm | | 150 µm |
| Maximum DC current | 500 mA (2 A for -HC version)* | | 500 mA |
| Thermal range | -65 to 125°C | | -65 to 125°C |
| Rc on aluminum (gold) | Typically < 0.05 Ω (< 0.02 Ω) | | Typically < 0.05 Ω (< 0.02 Ω) |
| Rc variation during one 5-hour single contact cycle** | 10 mΩ | | 10 mΩ |
| Min. probe pad size | 25 x 35 µm (best case) | | 25 x 35 µm (best case) |

* High-current version (2 A) available up to 67 GHz (GSG only).

**Specifications applicable at 25°C operating temperature on clean aluminum.

Recommended Impedance Standard Substrates

| Freq (GHz) | Config | Pitch | Part No. |
|------------|------------|------------|----------|
| DC to 40 | GSG | 100 to 250 | 101-190 |
| DC to 50 | GS/SG | 100 to 250 | 103-726 |
| DC to 67* | GSGSG, SGS | 100 to 125 | 129-239 |
| | | 150 to 225 | 129-240 |
| | GSSG | 250 | 129-241 |
| | | 100 to 150 | 129-246 |
| | | 200 to 250 | 129-247 |
| DC to 110* | GSG | 100 to 150 | 104-783 |
| DC to 325* | GSG | 50 to 75 | 138-356 |
| DC to 325* | GSG | 100 to 150 | 138-357 |

*Use of absorbing auxiliary chuck or absorbing ISS holder (p/n 116-344) recommended

Cables for Use with Infinity Probes

| Freq (GHz) | Probe station | Body style | Length | Part number |
|------------|--------------------------------|------------|---------|-------------|
| DC to 40 | Summit™ 11K/12K, S300 | A | 48 inch | 132-423 |
| | | V | 48 inch | 132-420 |
| | M150, RF-1,9K, no MicroChamber | A | 48 inch | 124-084-B |
| | | V | 48 inch | 101-162-B |
| DC to 50 | Summit 11K/12K, S300 | A | 48 inch | 132-424 |
| | | V | 48 inch | 132-421 |
| | M150, RF-1,9K, no MicroChamber | A | 48 inch | 124-085-B |
| | | V | 48 inch | 103-202-B |
| DC to 67 | Summit 11K/12K, S300 | A | 36 inch | 132-425 |
| | | V | 36 inch | 132-422 |
| | M150, RF-1,9K, no MicroChamber | A | 36 inch | 124-606-B |
| | | V | 36 inch | 124-605-B |
| DC to 110 | Summit 11K/12K, S300 | A, V | 18 cm | 132-458 |
| | Elite300™ | A, V | 24 cm | 147-316 |

'A' denotes 45° angled coaxial connector body style.

'V' denotes vertical coaxial connector body style.

WAVEGUIDE INFINITY PROBES

For each rectangular waveguide designation there are two different probe models.

The "T" models are designed to be compatible with Cascade Microtech's Summit 11000/12000, S300 and Elite300 probing stations.

These models are also TopHat™ compatible when used with TopHat PNs 116-441 and 115-164.

The "S" probe models are compatible with Cascade Microtech's 150mm probing stations.

All models are available without bias network by request.

For Elite300 version waveguide, consult with Cascade Microtech or your local representative for compatibility.

| | Body style "T" (tall) | Body style "S" (short) |
|--|--|--|
| Waveguide designator (Frequency range) | | |
| WR3 (220 to 325 GHz) | I325-T-GSG-xxx-BT | I325-S-GSG-xxx-BT |
| WR5 (140 to 220 GHz) | I220-T-GSG-xxx-BT | I220-S-GSG-xxx-BT |
| WR6 (110 to 170 GHz) | I170-T-GSG-xxx-BT | I170-S-GSG-xxx-BT |
| WR8 (90 to 140 GHz) | I140-T-GSG-xxx-BT | I140-S-GSG-xxx-BT |
| WR10 (75 to 110 GHz) | I110-T-GSG-xxx-BT | I110-S-GSG-xxx-BT |
| WR12 (60 to 90 GHz) | I90-T-GSG-xxx-BT | I90-S-GSG-xxx-BT |
| WR15 (50 to 75 GHz) | I75-T-GSG-xxx-BT | I75-S-GSG-xxx-BT |
| Typical insertion loss / return loss | | |
| I325 | 6.5 dB / 13 dB | 5 dB / 12 dB |
| I220 | 5.2 dB / 13 dB | 4 dB / 13 dB |
| I170 | 4.7 dB / 13 dB | 4 dB / 13 dB |
| I140 | 3.1 dB / 13 dB | 3 dB / 13 dB |
| I110 | 2.6 dB / 13 dB | 2 dB / 13 dB |
| I90 | 2.6 dB / 13 dB | 2 dB / 13 dB |
| I75 | 2.1 dB / 13 dB | 1.5 dB / 13 dB |
| Electrical repeatability | -60 dB | -60 dB |
| Probe pitch [25 µm increments] | 50 to 100 µm (WR3, WR5, WR6, and WR8) 50 to 150 µm (WR10, WR12, and WR15) | 50 to 100 µm (WR3, WR5, WR6, and WR8) 50 to 150 µm (WR10, WR12, and WR15) |
| Recommended overtravel | 25 to 50 µm | 25 to 50 µm |
| Maximum safe overtravel | 100 µm | 100 µm |
| Maximum DC current | 500 mA | 500 mA |
| Thermal range | -65 to 125°C | -65 to 125°C |
| Rc on aluminium | Typically < 0.05 Ω | Typically < 0.05 Ω |
| Rc on gold | Typically < 0.02 Ω | Typically < 0.02 Ω |
| Rc variation during one 5-hour single contact cycle* | 10 mΩ | 10 mΩ |
| Minimum probe pad size | 25 x 35 µm (best case) | 25 x 35 µm (best case) |

*Specifications applicable at 25°C operating temperature on clean aluminum.

Recommended Impedance Standard Substrates

| Model | Config | Pitch (µm) | Part No. |
|-------|--------|------------------------|--------------------|
| WR3* | GSG | 50 to 75 100 to 150 | 138-356 138-357 |
| WR5* | | | |
| WR6* | | | |
| WR8* | | | |
| WR10* | | | |
| WR12* | | | |
| WR15* | | | |

*Use of absorbing auxiliary chuck or absorbing ISS holder (p/n 116-344) recommended

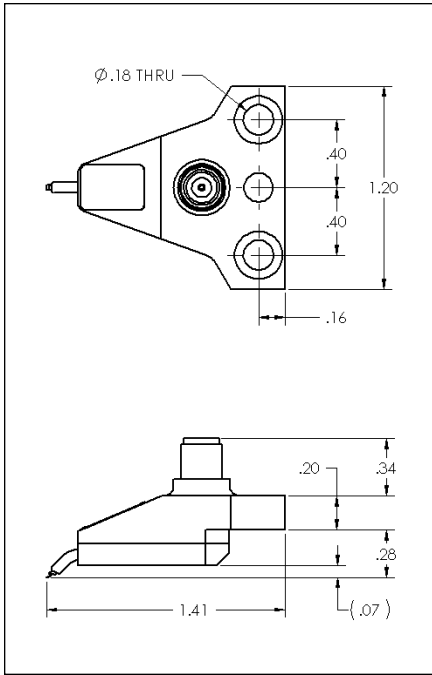
Waveguide Sections for Use with Waveguide Infinity Probes

*For Elite300 version waveguide, consult with Cascade Microtech for compatibility.

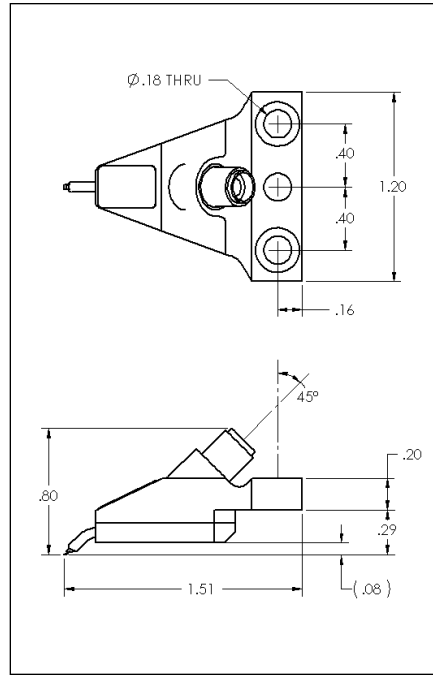
| Waveguide "T" model | Waveguide S-bend section |
|---------------------|------------------------------------|
| WR3 | 147-309 (147-310 for Elite 300) |
| WR5 | 133-994 |
| WR6 | 133-995 |
| WR8 | 133-996 |
| WR10 | 133-997 |
| WR12 | 133-998 |
| WR15 | 133-999 |

| Waveguide "S" model | Waveguide S-bend section |
|---------------------|--------------------------|
| WR3 | 144-399 |
| WR5 | 133-988 |
| WR6 | 133-989 |
| WR8 | 133-990 |
| WR10 | 133-991 |
| WR12 | 133-992 |
| WR15 | 133-993 |

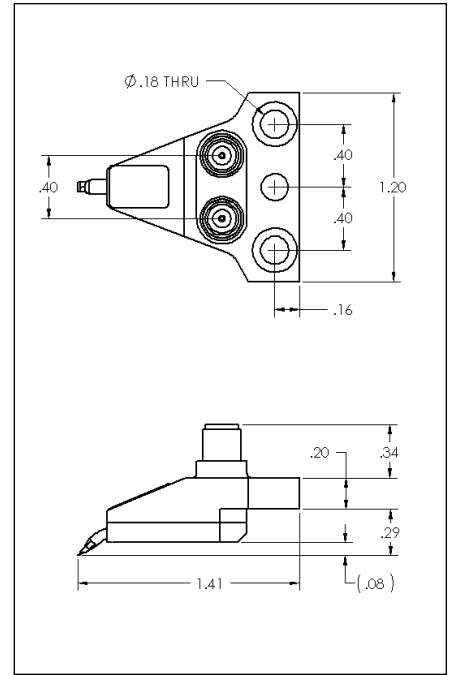
INFINITY PROBES



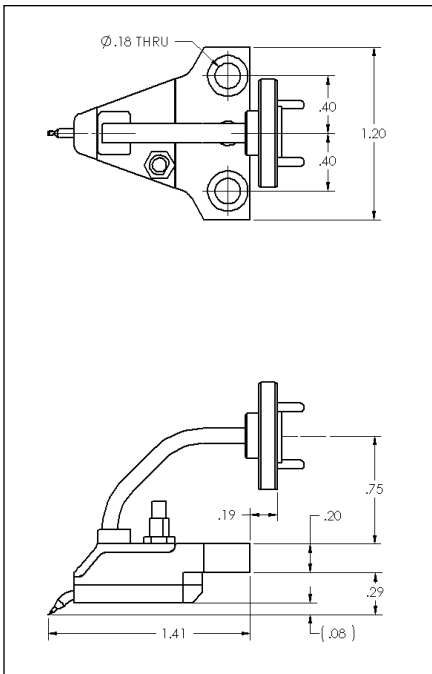
Infinity Probe, vertical body style



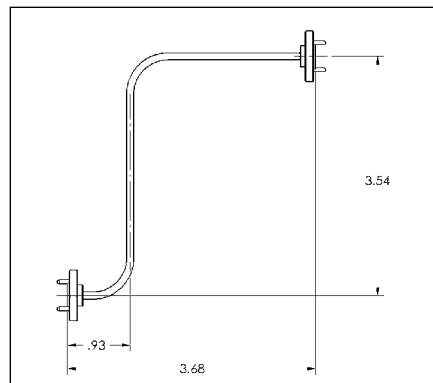
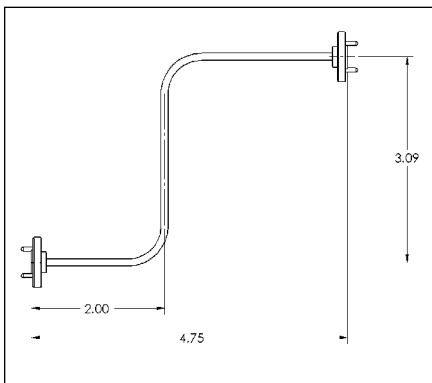
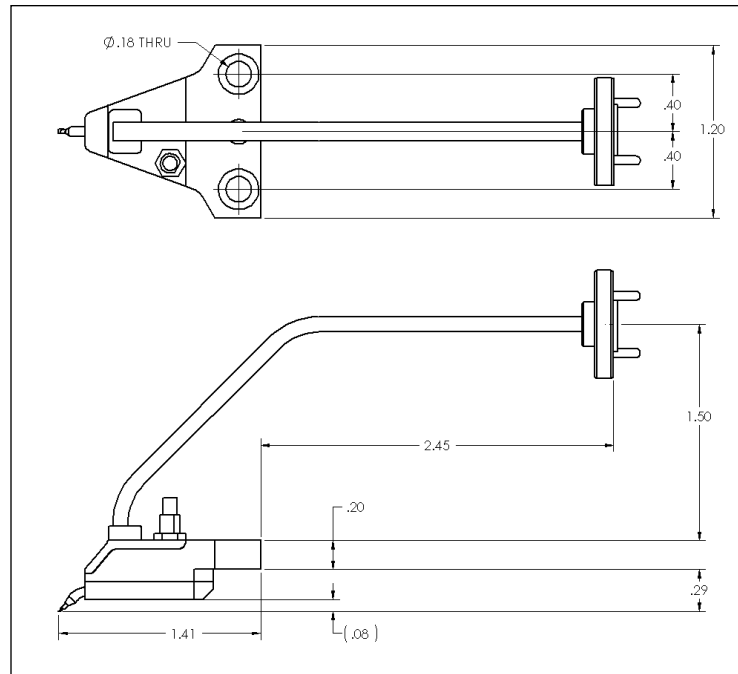
Infinity Probe, angled body style



Dual Infinity Probe



Waveguide Infinity Probe - "S" Model on the left, and "T" Model on the right



Waveguide S-bend for Waveguide S & T models: left for 9k probe stations, right for Summit 11K/12K and S300 stations.

Note: Additional versions are available for the Elite300 probe station and for the I325 probe. Consult with factory for more information

T-WAVE PROBES



Industry-leading performance for on-wafer measurement of millimeter and sub-millimeter wavelength devices

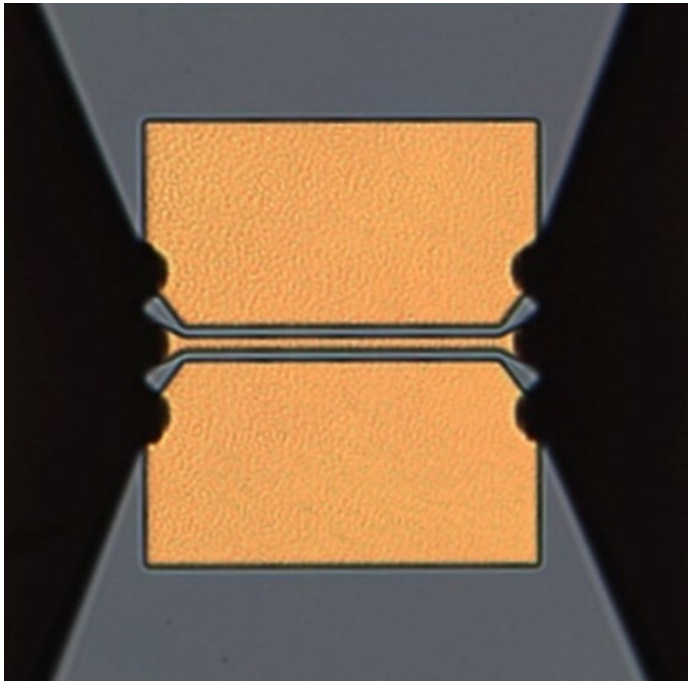
The T-Wave Probes set the industry performance standard for characterization of mmWave devices. This probe delivers low insertion loss and low contact resistance when probing gold pads.

Features

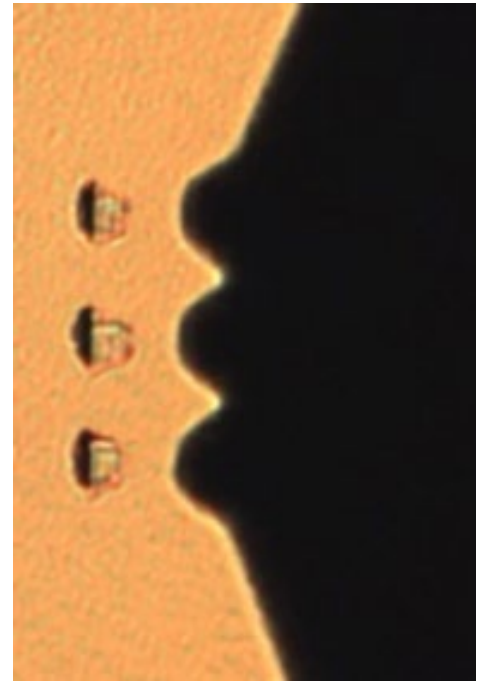
- Low insertion loss
- Low contact resistance
- 140 GHz – 1.1 THz versions
- Probe pitch as narrow as 25 μm
- Lithographically-defined probe tip
- Nickel contacts

Advantages

- Excellent tip visibility
- Ability to characterize 1.1 THz devices
- Typical Insertion loss < 1.5 dB between 140 and 220 GHz
- Integrated DC bias-T with low-profile GPPO connector



T-Wave Probes contacting a CPW thru line



Typical scrub marks of the T-Wave Probes

T-WAVE PROBES

The 220, 260, and 330 GHz waveguide probes come in two different models. The "T" body style is compatible with Cascade Microtech's Summit 11000/12000, S300 and Elite300 probe stations. The "S" body style is compatible with Cascade Microtech's 150 mm probe stations. All models are available without bias-T by request.

| | Body Style "T" | Body Style "S" |
|---|--|--|
| Waveguide designator (Frequency Range) | | |
| WR1.0 (750 GHz – 1.1THz) | T1100-GSG-25 (Low profile probe) | |
| WR1.5 (500 GHz – 750 GHz) | T750-GSG-25 (Low profile probe) | |
| WR2.2 (325 GHz – 500 GHz) | N/A | T500-S-GSG-xx |
| WR3.4 (220 GHz – 330 GHz) | T330-T-GSG-xxx | T330-S-GSG-xxx |
| WR4.3 (170 GHz – 260 GHz) | T260-T-GSG-xxx | T260-S-GSG-xxx |
| WR5.1 (140 GHz – 220 GHz) | T220-T-GSG-xxx | T220-S-GSG-xxx |
| Typical Insertion Loss / Return Loss | | |
| T1100 | 7 dB / 15 dB | |
| T750 | 5 dB / 15 dB | |
| T500 | N/A | 4.5 dB / 15 dB |
| T330 | 4.3 dB / 15 dB (typical) | 2.9 dB / 15 dB (typical) |
| T260 | 3.2 dB / 15 dB (typical) | 2.2 dB / 15 dB (typical) |
| T220 | 2.3 dB / 15 dB (typical) | 1.5 dB / 15 dB (typical) |
| Probe pitch (25 µm increments) | 25 µm (WR1.0 and WR1.5) 25 µm, 50 µm (WR2.2) 25-100 µm (WR3.4, WR4.3, WR5.1) | 25 µm (WR1.0 and WR1.5) 25 µm, 50 µm (WR2.2) 25-100 µm (WR3.4, WR4.3, WR5.1) |
| Recommended overtravel | 10 µm (Au) 25-35 µm (Al) | 10 µm (Au) 25-35 µm (Al) |
| Maximum safe overtravel | 60 µm | 60 µm |
| Maximum DC current | 500 mA | 500 mA |
| Rc on Al | Typically < 0.30 Ω | Typically < 0.30 Ω |
| Rc on Au | Typically < 0.04 Ω | Typically < 0.04 Ω |
| Rc variation during one 5-hour single contact cycle | N/A | N/A |
| Minimum probe pad size | 25 x 40 µm for passivation windows, 15 x 15 µm Au/no pass (both best cases) | 25 x 40 µm for passivation windows, 15 x 15 µm Au/no pass (both best cases) |

Contact Cascade Microtech for waveguide sections.

Recommended Impedance Standard Substrates

| Model | Config | Pitch (µm) | Part No. |
|-------|--------|------------|--|
| WR1.0 | GSG | 25 | 165-731 |
| WR1.5 | | 25 | 165-734 |
| WR2.2 | | 25, 50 | 165-735 165-736 |
| WR3.4 | | 25 to 100 | 165-737 165-738 165-739 165-740 |
| WR4.3 | | | 165-741 165-742 165-743 165-744 |
| WR5.1 | | | 165-745 165-746 165-747 165-748 |

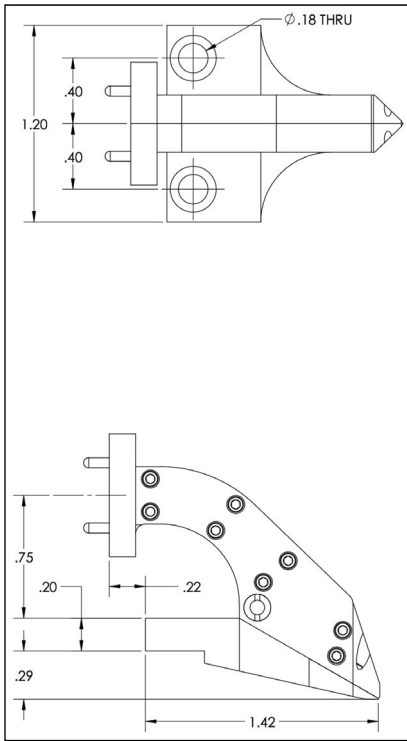
Waveguide Sections for Use with Waveguide Infinity Probes

*For Elite300 version waveguide, consult with Cascade Microtech for compatibility.

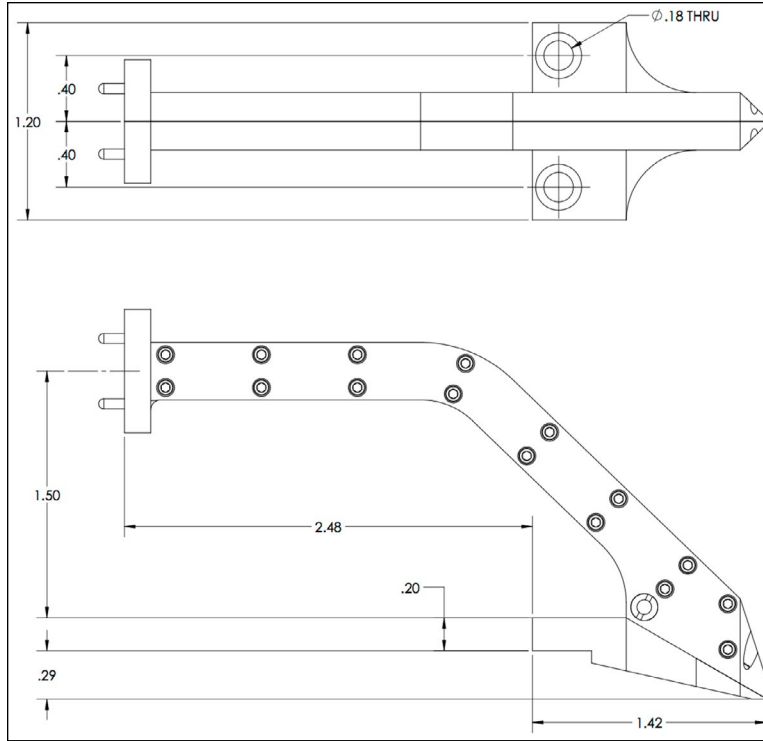
| Waveguide "T" model | Waveguide S-bend section |
|---------------------|--------------------------|
| WR3.4 | 147-309 |
| WR4.3 | 165-696 |
| WR5.1 | 133-994 |

| Waveguide "S" model | Waveguide S-bend section |
|---------------------|--------------------------|
| WR3.4 | 144-399 |
| WR4.3 | 165-698 |
| WR5.1 | 133-988 |

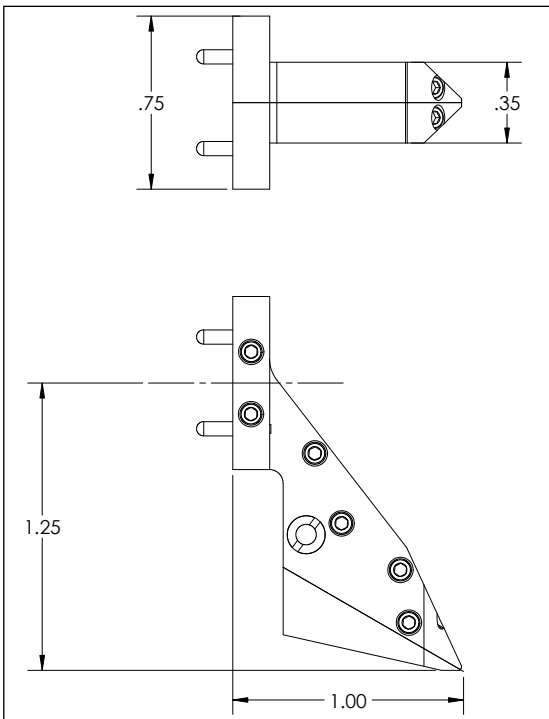
T-WAVE PROBES



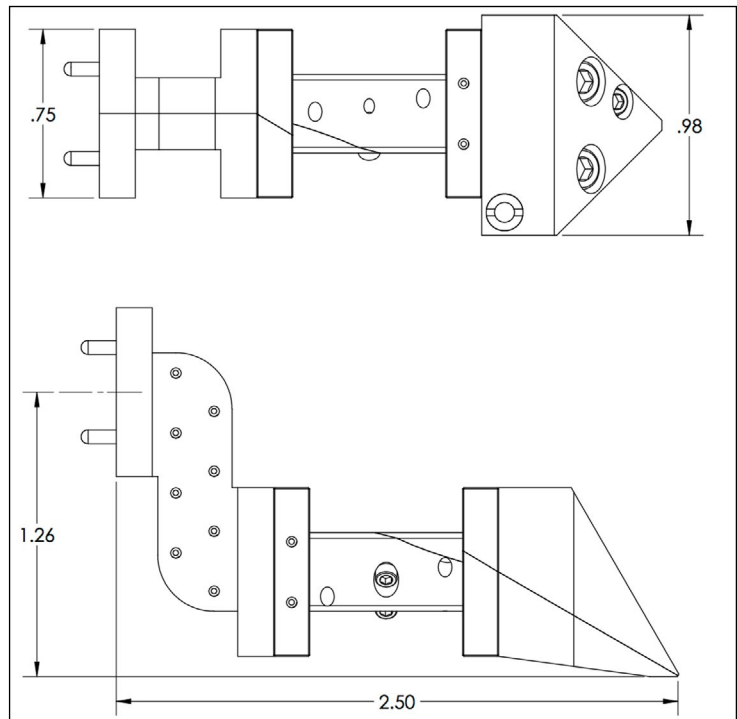
T-Wave Probe - "S" Model



T-Wave Probe - "T" Model



T-Wave Probe - 1.1 THz Model



T-Wave Probe - 750 GHz Model

AIR COPLANAR PROBES



RF and microwave on-wafer probes: long-lasting, rugged, ACP series

The Air Coplanar Probe was developed in response to the need for a rugged microwave probe with a compliant tip for accurate, repeatable measurements on-wafer. Air Coplanar Probes feature excellent probe-tip visibility and the lowest loss available. For measurements where pad area is at a premium, the ACP family is offered with a reduced contact (RC)* area probe tip. The ACP probe family also features dual signal line versions for differential and multiport measurements.

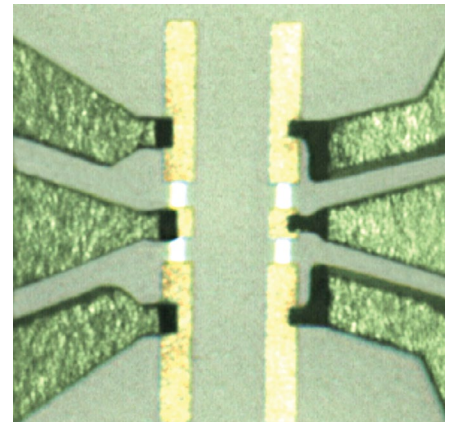
Combining outstanding electrical performance with precise probe mechanics, the ACP probe is the most widely used microwave probe available.

Features

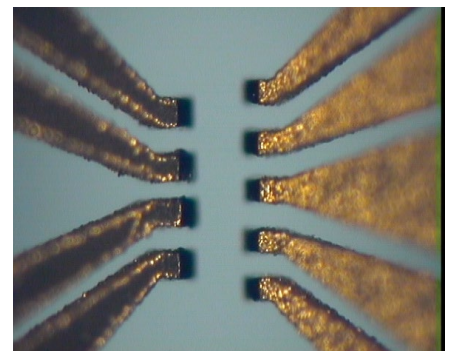
- Unique Air Coplanar tip design
- DC to 110 GHz models available in single and dual line versions
- Low insertion and return loss with ultra-low-loss (-L) versions
- Excellent crosstalk characteristics
- Wide operating temperature -65°C to +200°C
- Wide range of pitches available up to 1250 μm
- Fast delivery available on 100, 125, 150, 200, and 250 μm pitched probes
- Individually supported contacts
- Choice of beryllium copper (BeCu) or tungsten tip material
- Reduced contact (RC) probe tips for small pads
- Precision tip dual configuration available
- BeCu tip provides rugged, repeatable contact on gold pads

Advantages

- Good visibility at probe tip allows accurate placement on DUT contact-pads
- Outstanding compliance for probing non-planar surfaces
- Stable and repeatable over-temperature measurements
- Typical probe life of 500,000 touchdowns on gold pads
- Reduction in development cycle time



Standard ACP tip (left) versus reduced contact ACP tip (right)



ACP-GSSG (left) vs. ACP-GSGSG (right)

*For pad sizes smaller than 80 μm , use reduced contact area (RC) tips.

AIR COPLANAR PROBES

| | Probe head type | Part number (Note 1,2) | Insertion loss Max. (dB) (Note 12) | Max DC current* | Max RF power** | MicroChamber compatible | Connector | Recommended ISS | |
|---------------------------------------|--------------------------------------|---------------------------|--|--------------------|-------------------|----------------------------|-------------------------------|-----------------------------|--------------------------------|
| | | | | | | | | Standard (100 to 250 μm) | Wide pitch (250 to 1250 μm) |
| Single Coaxial | DC to 40 GHz (Notes 1, 2, 11) | ACP40-m-GS-xxx | 2.0 | 5 A | 6.5 W | Yes | 2.92 mm (f) | 103-726 | 106-683 |
| | | ACP40-m-SG-xxx | 2.0 | 5 A | 6.5 W | Yes | | 103-726 | 106-683 |
| | | ACP40-m-GSG-xxx | 1.0 | 5 A | 6.5 W | Yes | | 101-190 | 106-682 |
| | | ACP40-Am-GS-xxx | 2.0 | 5 A | 6.5 W | (Note 7) | 2.92 mm (f) | 103-726 | 106-683 |
| | | ACP40-Am-SG-xxx | 2.0 | 5 A | 6.5 W | (Note 7) | | 103-726 | 106-683 |
| | | ACP40-Am-GSG-xxx | 1.0 | 5 A | 6.5 W | (Note 7) | | 101-190 | 106-682 |
| | ACP40-Lm-GSG-xxx | 0.6 (Note 6) | 5 A | 6.5 W | (Note 7) | 101-190 | | 106-682 | |
| | DC to 50 GHz (Notes 1, 2, 11) | ACP50-m-GS-xxx | 2.0 @ 40 GHz | 5 A | 5 W | Yes | 2.4 mm (f) | 103-726 | n/a |
| | | ACP50-m-SG-xxx | 2.0 @ 40 GHz | 5 A | 5 W | Yes | | 103-726 | |
| | | ACP50-m-GSG-xxx | 1.4 | 5 A | 5 W | Yes | | 101-190 | |
| | | ACP50-Am-GS-xxx | 2.0 @ 40 GHz | 5 A | 5 W | (Note 7) | 2.4 mm (f) | 103-726 | n/a |
| | | ACP50-Am-SG-xxx | 2.0 @ 40 GHz | 5 A | 5 W | (Note 7) | | 103-726 | |
| | | ACP50-Am-GSG-xxx | 1.4 | 5 A | 5 W | (Note 7) | | 101-190 | |
| | ACP50-Lm-GSG-xxx | 1.4 | 5 A | 5 W | (Note 7) | 101-190 | | | |
| | DC to 65 GHz (Notes 1, 2, 11) | ACP65-m-GS-xxx | 2.0 @ 40 GHz | 5 A | 4 W | Yes | 1.85 mm (f) | 103-726 (Note 8) | n/a |
| | | ACP65-m-SG-xxx | 2.0 @ 40 GHz | 5 A | 4 W | Yes | | 103-726 (Note 8) | |
| | | ACP65-m-GSG-xxx | 2.0 | 5 A | 4 W | Yes | | 101-190 (Note 8) | |
| | | ACP65-Am-GS-xxx | 2.0 @ 40 GHz | 5 A | 4 W | (Note 7) | 1.85 mm (f) | 103-726 (Note 8) | n/a |
| ACP65-Am-SG-xxx | | 2.0 @ 40 GHz | 5 A | 4 W | (Note 7) | 103-726 (Note 8) | | | |
| ACP65-Am-GSG-xxx | | 2.0 | 5 A | 4 W | (Note 7) | 101-190 (Note 8) | | | |
| ACP65-Lm-GSG-xxx | 2.0 | 5 A | 4 W | (Note 7) | 101-190 (Note 8) | | | | |
| DC to 110 GHz (Notes 1, 2, 10, 11) | ACP110-Cm-GSG-xxx | 1.25 | 5 A | 2 W | Yes | 1.0 mm (f) | 104-783 (Note 8) | n/a | |
| | ACP110-Am-GSG-xxx | 1.25 | 5 A | 2 W | (Note 7) | | 104-783 (Note 8) | | |
| | ACP110-Lm-GSG-xxx | 1.15 | 5 A | 2 W | (Note 7) | | 104-783 (Note 8) | | |
| Dual coaxial | DC to 110 GHz (Notes 1, 2, 3, 10) | ACPyy-Dm-GSGSG-xxx | 1.25 @ 40 GHz (Note 4) | 5 A | 2 W | Yes | User specified (Note 3) | See ISS list (page 30) | See ISS list (page 30) |
| | | ACPyy-Dm-GSGS-xxx | 1.25 @ 18 GHz (Note 4) | 5 A | 2 W | Yes | | | |
| | | ACPyy-Dm-GSS-xxx | 1.0 @ 10 GHz (Note 4,5) | 5 A | 2 W | Yes | | | |
| | | ACPyy-Dm-GSSG-xxx | 1.0 @ 10 GHz (Notes 4) | 5 A | 2 W | Yes | | | |
| | | ACPyy-Dm-SGS-xxx | 1.25 @ 18 GHz (Notes 4) | 5 A | 2 W | Yes | | | |
| | | ACPyy-Dm-SGSG-xxx | 1.25 @ 18 GHz (Notes 4) | 5 A | 2 W | Yes | | | |
| Waveguide | 50 to 75 GHz (Notes 1, 2, 10) | ACP75-Sm-GSG-xxx | 1.5 | 500 mA | 4 W | No | WR-15 | 104-783 (Note 8) | n/a |
| | | ACP75-Tm-GSG-xxx | 2.0 | 500 mA | 4 W | Yes | WR-15 | 104-783 (Note 8) | n/a |
| | 60 to 90 GHz (Notes 1, 2, 10) | ACP90-Sm-GSG-xxx | 2.0 | 500 mA | 3 W | No | WR-12 | 104-783 (Note 8) | n/a |
| | | ACP90-Tm-GSG-xxx | 2.5 | 500 mA | 3 W | Yes | WR-12 | 104-783 (Note 8) | n/a |
| | 75 to 110 GHz (Notes 1, 2, 10) | ACP110-Sm-GSG-xxx | 2.0 | 500 mA | 2 W | No | WR-10 | 104-783 (Note 8) | n/a |
| | | ACP110-Tm-GSG-xxx | 2.5 | 500 mA | 2 W | Yes | WR-10 | 104-783 (Note 8) | n/a |
| 90 to 140 GHz (Notes 1, 2, 10) | ACP140-Sm-GSG-xxx | 2.5 | 500 mA | 2 W | No | WR-8 | 138-356/357 (Note 8) | n/a | |
| | ACP140-Tm-GSG-xxx | 3.0 | 500 mA | 2 W | Yes | WR-8 | 138-356/357 (Note 8) | n/a | |

*2.5 A for W tip, 5 A for BeCu tip, and 1 A for RC tip.

All specs are for probe and DUT at room temperature.

**Rated at highest probe frequency. Additionally each probe is capable of > 30W @ 2.4 GHz, > 10W @ 18 GHz, > 7.5W @ 26.5 GHz.

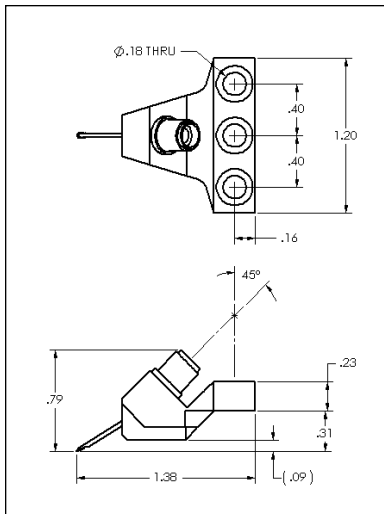
Notes:

- m** refers to the tip material. Delete for BeCu. Change to **W** for tungsten.
- xxx** refers to probe contact center to center spacing in microns, e.g. ACP40-GSG-150 is 150 μm. Contacts are on a constant pitch and width is approximately 50 μm.
- yy** refers to the connector type. 40 (2.92mm), 50 (2.4 mm), 65 (1.85 mm), 110 (1.0 mm).
- Insertion loss specification is for a 2.92mm connectorized probe.
- Signal furthest from ground is not specified.
- Low-loss probe insertion loss for pitches greater than 150 μm and less than or equal to 250 μm is 0.8 dB.
- Requires new larger top hat assembly.
- Use of 116-344 ISS absorber recommended.
- The convention for describing probe head footprints is the sequence of contacts as seen looking down on the probe head tip in its functional position, with the tip pointing away from the viewer, describing contacts from left to right.
- ACP probes, except 110 models, are available in a wide range of pitches from 50 μm to 1250 μm. Insertion loss and frequency performance applies to pitches from 100 to 250 μm, unless otherwise noted. ACP110 probes available in pitches from 100 to 150 μm; minimum pitch for ACP dual probes is 100 μm.
- Angled probes require the 114-592 probe mount for cable clearance.
- Electrical specifications apply to probe pitches of 100 to 250 μm, except for 90, 110 and 140 GHz probes, where the maximum pitch is 150 μm.

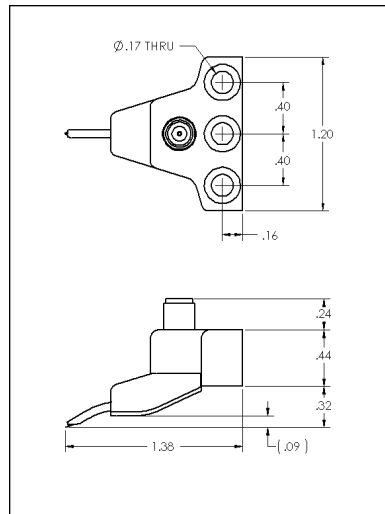
Part Numbers for Reduced Contact Probes

ACP Reduced Contact Probes are available in the same configurations and body styles as the regular ACP series. The standard available pitches are from 100 to 250 μm. Other pitches are available upon request. When ordering, add "**RC**" to the end of the regular ACP part number from the above, e.g. "ACP40-W-GSG-150**RC**"

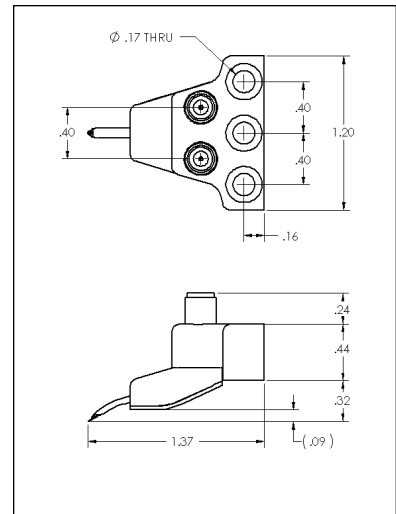
AIR COPLANAR PROBES



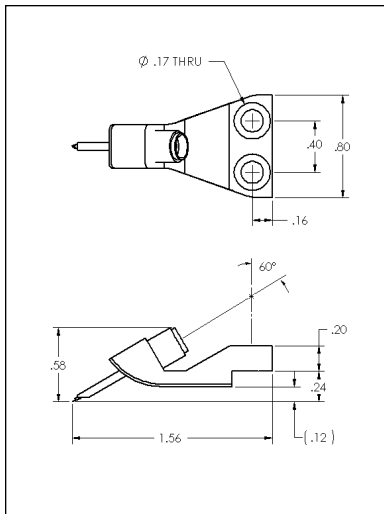
Probe style for: ACP40-Ax, ACP50-Ax, ACP65-Ax, ACP110-Ax.



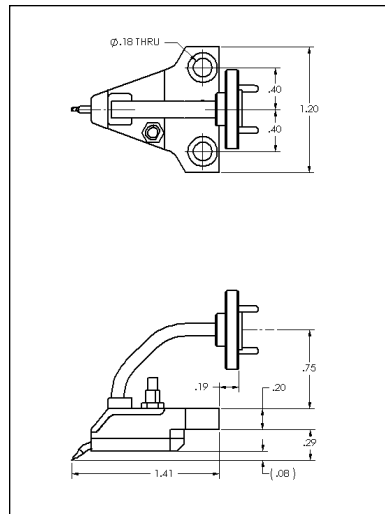
Probe style for: ACP40-x, ACP50-x, ACP65-x, ACP110-Cx.



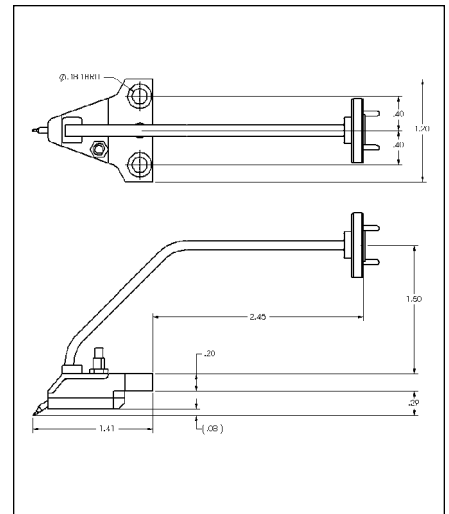
Probe style for: ACP40-Dx, ACP50-Dx, ACP65-Dx, ACP110-Dx.



Probe style for: ACP40-Lx, ACP50-Lx, ACP65-Lx, ACP110-Lx.



Waveguide ACP Probe - "S" Model on the left, and "T" Model on the right.



Cables for Use with Air Coplanar Probes

| Freq (GHz) | Probe station | Body style | Length (inch) | Part number |
|------------|--------------------------------|------------|---------------|-------------|
| DC to 40 | Summit 11K/12K, S300 | A | 48 inch | 132-423 |
| | | V | 48 inch | 132-420 |
| | M150, RF-1,9K, no MicroChamber | A | 48 inch | 124-084-B |
| | | V | 48 inch | 101-162-B |
| DC to 50 | Summit 11K/12K, S300 | A | 48 inch | 132-424 |
| | | V | 48 inch | 132-421 |
| | M150, RF-1,9K, no MicroChamber | A | 48 inch | 124-085-B |
| | | V | 48 inch | 103-202-B |
| DC to 65 | Summit 11K/12K, S300 | A | 36 inch | 132-425 |
| | | V | 36 inch | 132-422 |
| | M150, RF-1,9K, no MicroChamber | A | 36 inch | 124-606-B |
| | | V | 36 inch | 124-605-B |
| DC to 110 | Summit 11K/12K, S300 | A, V | 18 cm | 132-458 |

'A' denotes 45° angled coaxial connector body style.

'V' denotes vertical coaxial connector body style.

For waveguide sections and cables for Elite300, consult with Cascade Microtech or your local representative for compatibility.

|Z| PROBES



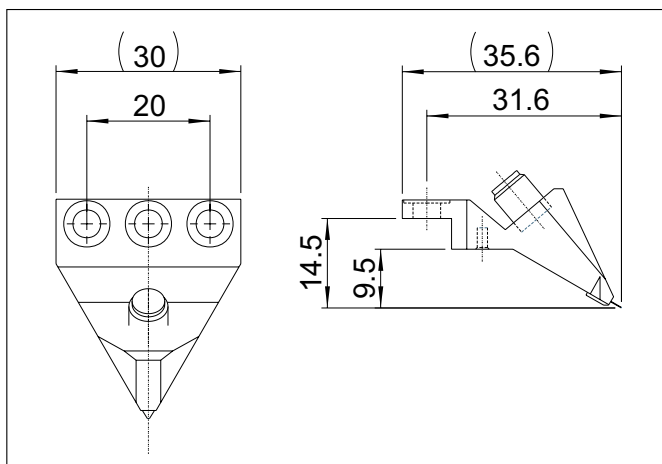
|Z| Probes for RF/Microwave Applications

Excellent performance over a temperature range from 10 K to 300°C with the long life time. Durable |Z| Probes enable easy and repeatable contacts to DUTs. Its robust design of the coplanar contact structure ensures long probe life time. The probe tips can move independently of one another, enabling probing of pad-height deviation of up to 50 µm.

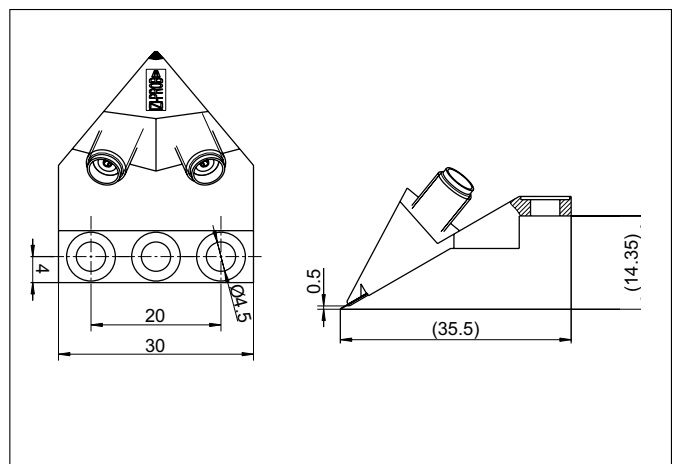
Features

- Long life time (typically > 1,000,000 touchdowns on Al pads)
- Independent, long contact springs to overcome pad height differences up to 50 µm
- Excellent performance in vacuum environments and in a wide temperature range (from 10 K to 300°C)
- High impedance control with perfectly-symmetrical coplanar contact structure, eliminating signal distortion

| Probe Type | Frequency | Connector | Configuration | Pitch | Application |
|----------------|-------------|------------|------------------|---------------|--|
| Z Probe | DC – 67 GHz | 1.85mm (f) | GSG, GS, SG | 50 - 1250 µm | Single-port RF |
| Dual Z Probe | DC – 50 GHz | 2.4mm (f) | GSGSG, GSSG, SGS | 100 - 500 µm | Multi-port/differential |
| Z Probe Power | DC – 40 GHz | 2.92mm (f) | GSG | 100 - 500 µm | High power/low loss |
| Z Probe PCB | DC – 20 GHz | 2.92mm (f) | GSG, GS, SG | 500 - 2500 µm | PCB, IC pins and ceramic substrate probing |



Probe style for |Z| Probes (mm)



Probe style for Dual |Z| Probes (mm)

For more details, visit www.cascademicrotech.com/products/probes

MULTI-CONTACT RF PROBES



InfinityQuad Probe

The first and only configurable multi-contact RF/mmW probe. For repeatable and precise engineering tests of DC, logic, RF and mmWave RFIC devices, the InfinityQuad probe ensures reliable measurement results up to 110 GHz over a wide temperature range (-40 to +125°C). The durable photo-lithographically defined fine-pitch tip structure enables probing of small pads down to 30 x 50 μm with minimum pad damage and consistent low contact resistance. The durable probe tips with small contact area of ~10 μm diameter ensure more than 250,000 touchdowns on Al pads and Au pads, and provide accurate X, Y and Z alignment.

For more details, visit www.cascademicrotech.com/products/probes/infinityquad and use our [online tool to capture your design](#) requirements and receive a quote.

Features

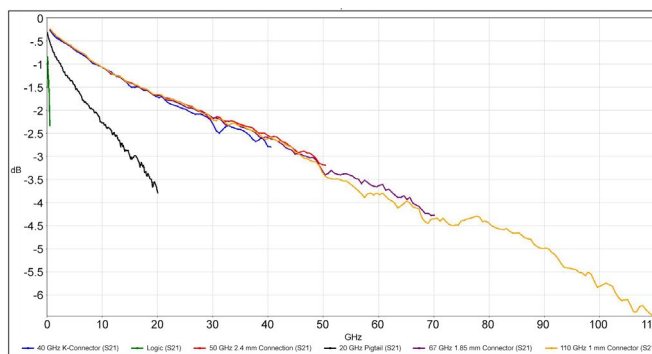
- Customizable configuration up to 25 contacts: RF, Eye-Pass power, ground, logic
- Fine-pitch probe tips enables probing of pitches as small as 75 μm and 30 x 50 μm pads
- Low and repeatable contact resistance on aluminum pads (< 0.05 Ω) ensures accurate results
- Durable probe structure ensures more than 250,000 contacts
- Intuitive design capture tool ensures accurate design and fast product delivery

Specifications

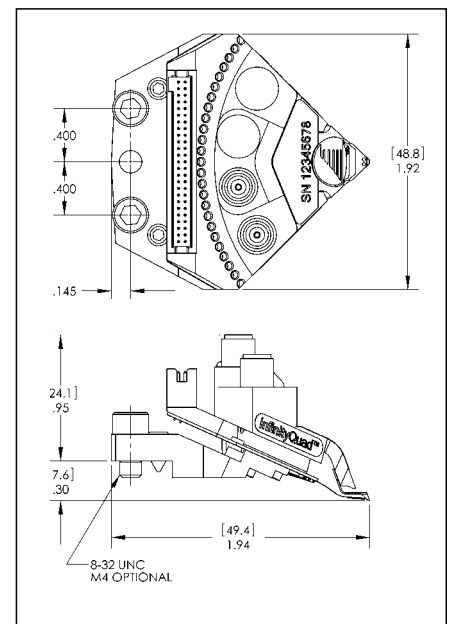
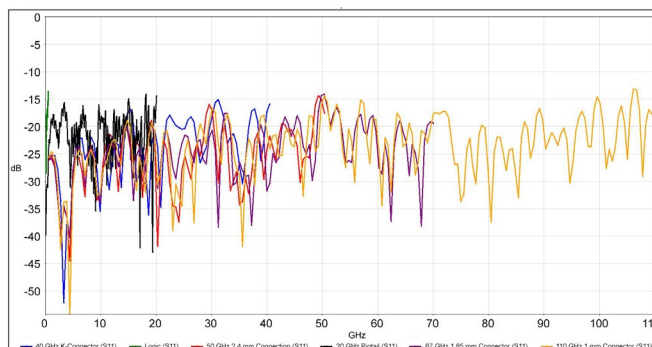
- Number of contacts: From 4 to 25
- Number of 'Premium' channels: Up to 4 Premium channels (40, 50, 67 or 110 GHz)
- Available contact pitch: 75, 80, 100, 125, 150, 200 and 250 μm
- Tip material: Non-oxidizing nickel alloy tips
- Minimum pad size: 30 x 50 μm (see Pad layout rules for details)
- Contact area: 12 x 8 μm (nominal)
- Operating temperature: -40°C to +125°C (max. -55°C to +150°C)
- Contact life: > 250,000 touchdowns
- Recommended overtravel: 50 - 75 μm
- Maximum safe overtravel: > 250 μm
- Maximum DC current: 400 mA
- Maximum DC voltage: 50 V power bypass (100 V other)
- Series resistance (not including contact): < 2 Ω

Performance:

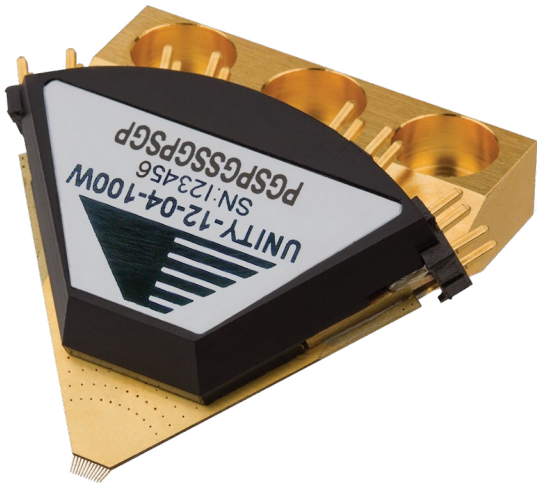
Insertion loss



Return loss



MULTI-CONTACT RF PROBES



Unity Probe

The multi-contact Unity Probe provides highly flexible configurability, unprecedented durability and ease-of-use for RFIC engineering test. Unlike “bent-to-order” needle-probe solutions, Unity Probes are quickly “built to order” with a precision tip cluster featuring multiple independently compliant fingers to isolate chip components from probing stresses — maximizing probe life and durability. Each contact can be configured to one or several contact types and frequencies, and the Unity Probe delivers on the legendary quality you’ve come to expect from Cascade Microtech’s comprehensive suite of probing solutions.

Features

- Up to 12 contacts; any contact can be DC, Power, Logic to 500 MHz, or RF to 20 GHz
- Online design configuration tool helps you to specify your probe in minutes
- All designs are fully quadrant compatible
- Full solution includes probes, calibration substrates, stations, accessories and calibration software
- Scalable architecture for future needs

Electrical

- Maximum DC current: 1 A
- Maximum DC voltage: 50 V power bypass (>100 V other)
- Series resistance (not including contact): < 0.2 Ω
- Rc on aluminum at 25°C: < 0.1 Ω
- RF connector: Gore 100 series
- DC/Logic connector: Two 0.025 inch square pins on 0.100 inch pitch
- Eye-Pass bypass inductance: 0.4 nH

Mechanical

- Number of contacts: 3 to 12 (Missing contacts count toward max.)
- Available contact pitch: 100 to 250 μm (25 μm steps)
- Tip material: Beryllium copper (BeCu) or tungsten (W)
- Contact area: 50 x 50 μm (nominal)
- Contact life > 250 k touchdowns on aluminum pads, > 500 k touchdowns on gold pads

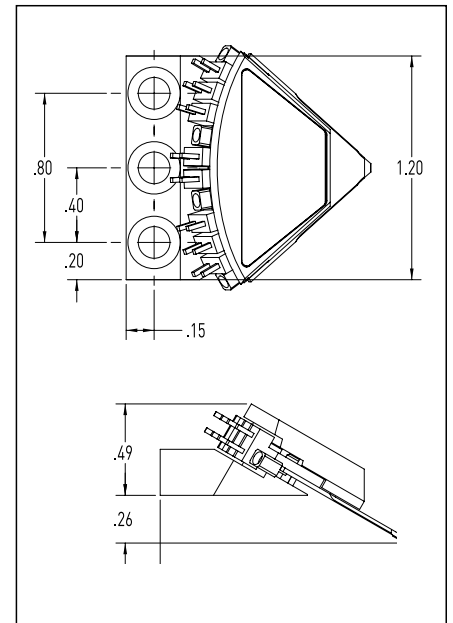
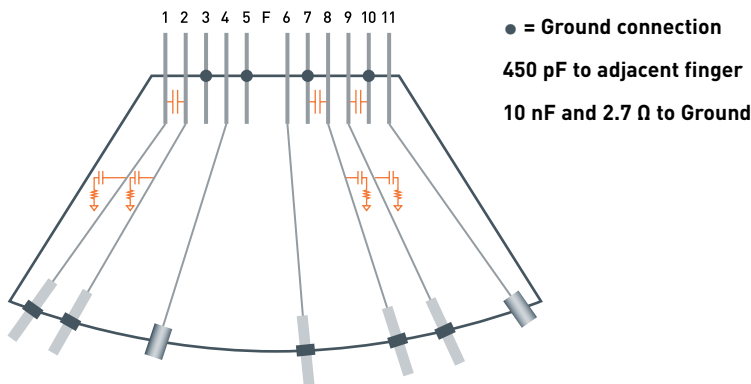
Ordering Information

See Unity Probe product page at www.cascademicrotech.com to learn how to create a configuration code.

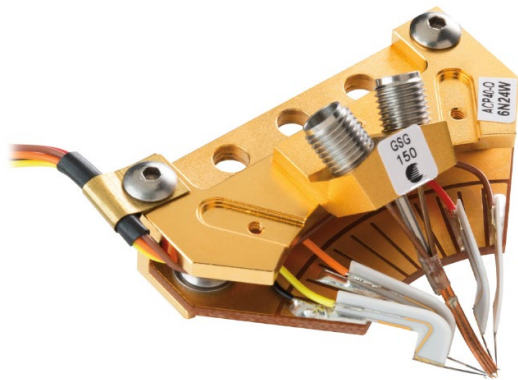
Optional cables available

- P/N 147-295 SMA Female to square pin 8 in. (20 cm) flex cable
- P/N 147-364 2.92 mm Female to Gore 100 8 in. (20 cm) flex cable

Sample Configuration: P'PGXLG'PP'G



MULTI-CONTACT RF PROBES



ACP Quadrant Probes

Quadrant Probes were developed in response to the need for multiple probe tips in a single module. Configurations consist of all RF or a combination of RF and DC.

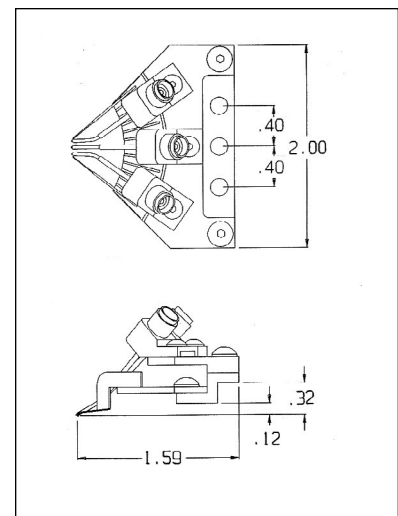
The RF probes use Air Coplanar technology to produce a rugged microwave probe with a compliant tip for accurate, repeatable measurements on-wafer. The DC probes use ceramic blade needles for low noise and high performance.

Features

- Customized to customer application
- Combination of DC and RF in a single probe module: One dual probe or a maximum of three RF Maximum of 9 DC standard (other quantities upon request).
- Utilizes ACP tip design, GSG, GS or SG
- RF tips available from DC to 110 GHz
- Choice of BeCu or tungsten tips
- DC power needles come standard with 100 pF microwave capacitor
- Consult factory for custom bypass components
- Power bypass inductance: 8 nH

Advantages

- Ideal for probing the entire circuit for functional test
- Dual ACP configuration supports differential signaling applications
- DC probes can provide power or slow logic to circuit under test



Probe style for: ACPyy-Q-1x, 2x & 30

| Probe head type | Part number | Number of RF probes | Number of DC probes |
|--------------------|-------------|---------------------|---------------------|
| ACP Quadrant Probe | ACPyy-Q-11 | 1 | 1 |
| | ACPyy-Q-12 | 1 | 2 |
| | ACPyy-Q-13 | 1 | 3 |
| | ACPyy-Q-14 | 1 | 4 |
| | ACPyy-Q-15 | 1 | 5 |
| | ACPyy-Q-16 | 1 | 6 |
| | ACPyy-Q-17 | 1 | 7 |
| | ACPyy-Q-18 | 1 | 8 |
| | ACPyy-Q-19 | 1 | 9 |
| | ACPyy-Q-21 | 2 | 1 |
| | ACPyy-Q-22 | 2 | 2 |
| | ACPyy-Q-23 | 2 | 3 |
| | ACPyy-Q-24 | 2 | 4 |
| | ACPyy-Q-25 | 2 | 5 |
| | ACPyy-Q-26 | 2 | 6 |
| | ACPyy-Q-27 | 2 | 7 |
| | ACPyy-Q-28 | 2 | 8 |
| | ACPyy-Q-30 | 3 | 0 |
| | ACPyy-Q-31 | 3 | 1 |
| | ACPyy-Q-32 | 3 | 2 |

| Connector | Probe station | Cable |
|-------------|---------------------------------|----------|
| 2.92 mm (f) | Summit 11K/12K, S300 | 132-423 |
| | M150, RF-1, 9K, no MicroChamber | 101-162B |
| 2.4 mm (f) | Summit 11K/12K, S300 | 132-424 |
| | M150, RF-1, 9K, no MicroChamber | 102-202B |
| 1.85 mm (f) | Summit 11K/12K, S300 | 132-425 |
| | M150, RF-1, 9K, no MicroChamber | 124-605B |
| 1.0 mm (f) | Elite300 | 147-316 |

Notes:

1. yy refers to the connector type: 40 (2.92 mm), 50 (2.4 mm), 65 (1.85 mm), 110 (1.0 mm).
2. Use Quadrant Probe Design Capture Form to specify quantity of RF and/or DC probes, pitch, tip material, configuration and cabling.
3. ACPyy-Q-2x or ACPyy-Q-3x require a minimum pitch of 1200 μ m.
4. A design capture form is available online to help with configuring and specifying the probe.

|Z| PROBES



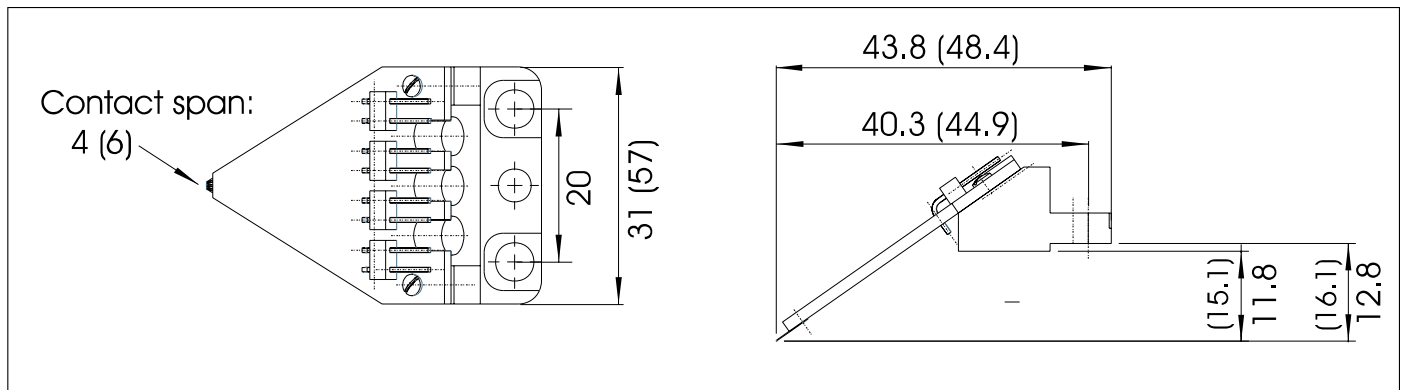
|Z| Probes for Mixed-Signal Applications

Accurate multi-contact probes with long life time for multiport and digital signal testing. Based on the durable |Z| Probe design, Multi |Z| Probes and ProbeWedge series allow up to 35 mixed-signal contacts on one probe, with optional on-board components. The Multi |Z| Probe can also be integrated into the QuadCard™ for high-throughput RF testing.

Features

- Mix DC and RF/Microwave contacts
- Long lifetime (typically > 1,000,000 touchdowns)
- Excellent performance in temperatures ranging from 10 K to 200°C
- Probe on any pad material with minimal damage

| Probe Type | Frequency | Configurable | Non-Uniform Pitch | Number of Contacts |
|-----------------|-------------|--------------|-------------------|--|
| Multi Z Probe | DC – 25 GHz | Yes | Yes | Up to 35 contacts; can be customized for larger quantities |
| HF ProbeWedge | DC – 67 GHz | Yes | Yes | Up to 12 contacts |
| ProbeWedge WE | DC – 20 GHz | Yes | Yes | Up to 40 contacts |
| ProbeWedge WD | DC – 20 GHz | Yes | Yes | Up to 16 contacts |



Multi |Z| Probe 3 to 7 pins with medium board size (mm).
Variational figures for Multi |Z| Probe 7 to 25 pins with large board size in brackets.

For more details, visit www.cascademicrotech.com/products/probes/

MULTI-CONTACT DC PROBES



Eye-Pass Probe

The Eye-Pass multi-contact DC probe is designed to provide a multitude of simultaneous connections to a wafer or similar devices. The connections may be ground, logic/signal, standard power and Eye-Pass power. For power-supply connections, Eye-Pass high-performance power-bypass technology delivers low impedance and resonance-free power connections over an extremely wide frequency range. Used with ACP-series probes and/or multi-contact RF Unity Probes, Eye-Pass probes provide functional at-speed testing for Known-Good-Die. Customized for the user-selected footprint that best suits your application, Eye-Pass probes feature up to 12 contacts per probe head, precisely aligned in a highly durable precision tip cluster to provide high compliance.

Features

- High-performance power bypassing for low-impedance and oscillation-free testing to more than 20 GHz
- Mix multiple contact types: Ground, Power (Standard or Eye-Pass), Logic/Signal
- Low and repeatable contact resistance on aluminum pads ($< 0.25 \Omega$ on Al, $< 0.01 \Omega$ on Au)
- Long probe life with more than 250 k touchdowns for moderate volume production test

Electrical

- Maximum DC current: 1 A
- Maximum DC voltage: 50 V power bypass (>100 V other)
- Series resistance: $< 1 \Omega$ (not including R_c)
- Connector: 2 x12 square pin header (ground row furthest from tip), Direct mapping of connector pins to contacts (no custom routing)
- Eye-Pass bypass inductance: 0.4 nH

Mechanical

- Number of contacts: 2 to 12 (Missing contacts count toward max.)
- Available contact pitch: 100 to 250 μm uniform spacing
- Tip material Beryllium copper (BeCu) for gold pads (Au) or tungsten (W)
- Contact area: 50 μm x 50 μm (nominal)
- Contact life > 250 k touchdowns on aluminum pads, > 500 k touchdowns on gold pads

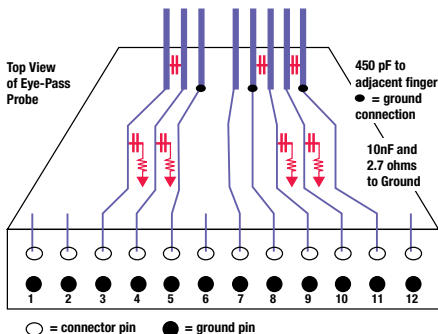
Ordering Information

See Eye-Pass Probe Design Capture page on Eye-Pass probe page at www.cascademicrotech.com to learn how to create a configuration code.

Optional cables available

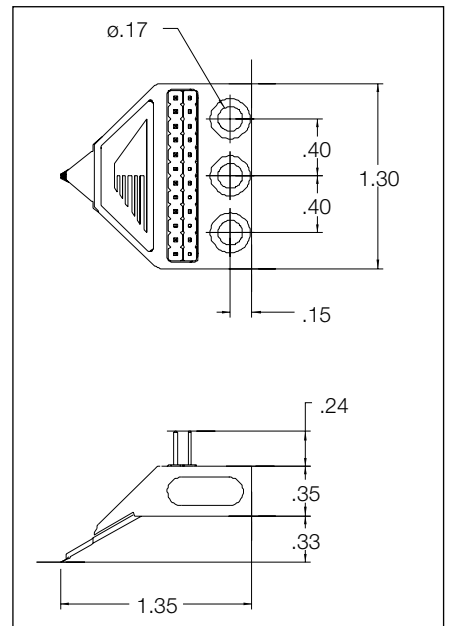
P/N 124-082 BNC Male to 2 pin Molex connector cable, 4ft length (single channel)

Sample Configuration: P'PGXLG'PP'G

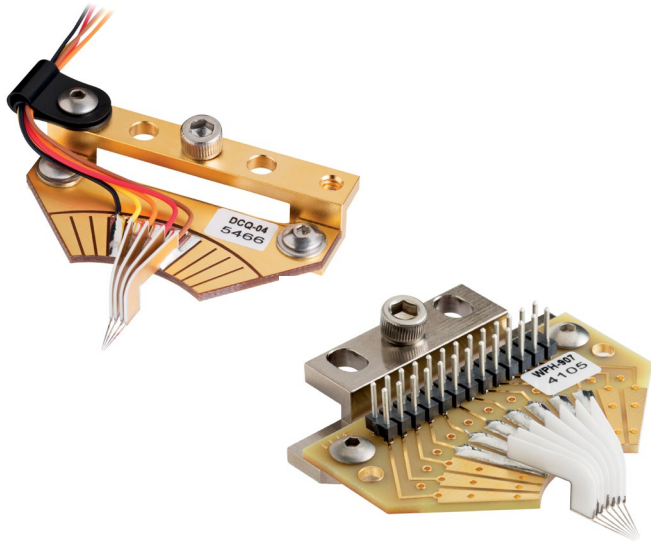


| Conn Pin number | Contact | Type |
|-----------------|---------|------------------|
| 1 | | No Contact |
| 2 | | No Contact |
| 3 | P | Eye-Pass Power** |
| 4 | P | Eye-Pass Power |
| 5 | G | Ground |
| 6 | X | No Contact |
| 7 | L | Logic/Signal |
| 8 | G | Ground |
| 9 | P | Eye-Pass Power |
| 10 | P | Eye-Pass Power |
| 11 | G | Ground |
| 12 | | No Contact |

**Adjacent ground recommended for best Eye-Pass Power performance



MULTI-CONTACT DC PROBES



Multiple configurations for functional circuit testing

The DCQ probes use controlled impedance, ceramic blade needles for low noise and high performance. This needle style allows the placement of high-quality bypass capacitors with very little series inductance due to their close proximity to the probe tip. All of the needles are connected to a common ground plane but individual needles can be easily (ground) isolated for additional low noise performance. A maximum of 16 needles are available for standard configurations and a maximum of 24 needles for custom configurations.

The WPH probes feature up to 12 ceramic-bladed, nickel-plated, tungsten needles with a 2 x 12 square pin cable interface. The circuit board has been laid out such that both series and shunt components can be added to the signal path of each needle.

Features

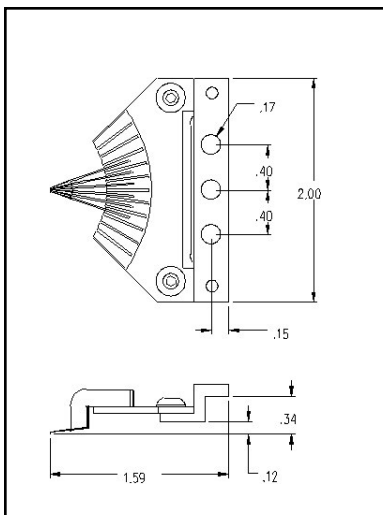
- Customized to customer application
- Up to 16 DC for standard; maximum of 24 DC for custom
- Standard DCQ probes have flat tip needles available in nickel-plated tungsten or BeCu with diameters of 0.75 mil, 1.0 mil and 1.5 mil. WPH

- probes have full-radius, nickel-plated tungsten needles.
- Supports collinear and non-standard needle configurations
- Power bypass inductance: DCQ 8 nH, WPH 16 nH

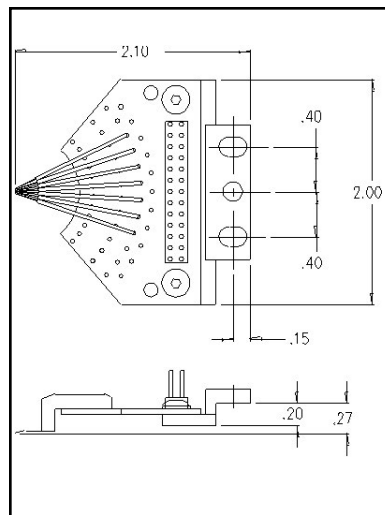
Advantages

- Ideal for probing the entire circuit for functional test
- DC probes can provide power or slow logic to circuit under test

| Probe head type | Part number (yy= number of DC probes) | Max. number of DC probes | MicroChamber compatible | Connector |
|---|---|-----------------------------|----------------------------|--|
| DCQ Quadrant probe custom version up to 24 (Note 1) | DCQ-yy | 16 | Yes (Note 5) | DCQ DC connections are supplied via a wire pig-tail to square pin header, standard. (Note 2) |
| WPH needle probe heads | WPH-9yy-xxx (Note 3) WPH-9yy-NS (Note 4) | 12 12 | No No | Circuit board mounted square-pin header, standard. |



Probe style for: DCQ-YY



Probe style for: WPH-9YY

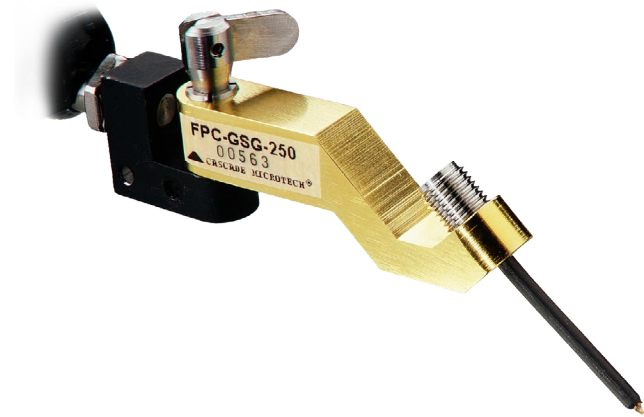
Notes:

1. Use Quadrant Probe Design Capture Form to specify number of DC needles and layout of DC lines.
2. Custom coax and triax cabling and/or connectors are available.
3. The -xxx suffix indicates probe contact center-to-center spacing (pitch) in microns, e.g. WPH-908-150 has 8 needles with a spacing of 150 μm (5.91 mils). Needles are in a collinear pattern with constant pitch.
4. Needles may be configured in a non-standard array and/or custom bypass components mounted on PCB.
5. MicroChamber compatibility up to 12 needles.

BOARD TEST AND SIGNAL INTEGRITY PROBES

Fixed-Pitch Compliant Probe (FPC)

The FPC-Series (Fixed-Pitch Compliant) is a high-frequency 50 Ω coaxial probe that offers a signal line with either one or two low-inductance fixed-pitch ground contacts. The probe tip structure is lithographically defined for unsurpassed impedance control, preserving the highest integrity possible when launching and receiving signals from SMT boards, hybrids and multi-chip modules (MCM).

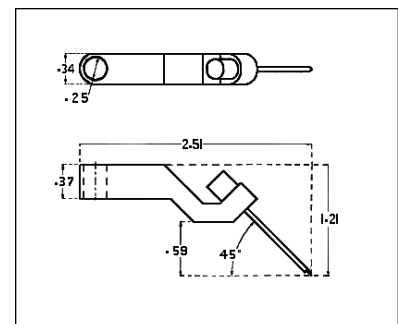


Features

- DC to 40 GHz bandwidth
- Maximum DC current: 5 A
- 10 ps rise time
- Low insertion and return loss
- 2 mils of tip-to-tip compliance
- High probing angle and clearance
- High-power handling capability

Advantages

- Maintains 50 Ω environment which allows accurate high-frequency measurement of microelectronic modules
- Compliant tips allow probing of non-planar structures
- BeCu tips provide longer probing life and reduce probe damage
- Access contacts close to components, module walls, or other obstructions



Probe style for: FPC

| Probe head type | Part number (Notes 1,2,3) | Insertion loss, typical | Return loss min. | Connector & tip type | Recommended cable | Recommended ISS (100 to 250 μm) | Wide pitch (250 to 1250 μm) |
|-----------------------|---------------------------|-------------------------|------------------|----------------------|-------------------|---------------------------------|-----------------------------|
| DC-40 GHz (Note 4, 5) | FPC-GS-xxx | 2.0 dB | | BeCu. | | 103-726 | 106-683 |
| | FPC-SG-xxx | 2.0 dB | 10 dB | 2.92 mm (f) | 124-084-B | 103-726 | 106-683 |
| | FPC-GSG-xxx | 1.0 dB | | | | 101-190 | 106-682 |
| DC-40 GHz (Note 4, 5) | FPC-W-GS-xxx | 2.0 dB | | Tungsten | | 103-726 | 106-683 |
| | FPC-W-SG-xxx | 2.0 dB | 10 dB | 2.92 mm (f) | 124-084-B | 103-726 | 106-683 |
| | FPC-W-GSG-xxx | 1.0 dB | | | | 101-190 | 106-682 |

Notes:

1. The -xxx suffix indicates probe contact center-to-center spacing (pitch) in microns, e.g. FPC40-SG-150 is 150 μm (5.91 mils). Contacts are on a constant pitch and width is approximately 50 μm.
2. The convention for describing probe head footprints is the sequence of contacts as seen looking down on the probe head tip in its functional position, with the tip pointing away from the viewer, describing contacts from left to right.
3. FPC standard pitches are 100, 125, 150, 200, 250, 350, 500, 650, 750, 1000 and 1250 μm. Non-standard pitches are available from 100 μm to 1250 μm and by special order to 3000 μm. Insertion loss applies to standard pitch range. Other pitches may have increased insertion loss. Adapter 106-835 is required for Summit Series positioners.

4. FPC GSG probes: 40 GHz up to 250 μm pitch, 20 GHz up to 1250 μm pitch and 3 GHz up to 3000 μm pitch.
FPC GS/SG probes: 40 GHz up to 250 μm pitch, 18 GHz up to 500 μm pitch, 10 GHz up to 1250 μm pitch and 3 GHz up to 3000 μm pitch.
5. FPC probes are not designed for use with MicroChamber probing stations.
6. Use the standard RF mount to FP adapter (P/N 104-913).

SPECIAL PURPOSE PROBES

Impedance Matching Probe

Cascade Microtech's Impedance Matching Probes, using proven Air Coplanar Probe technology, are available in both reactive and resistive versions. A choice of either ACP or FPC body styles is available.

Reactive matching probes provide low-loss transitions such as to the low impedance outputs of power devices. Resistive matching probes are frequently used to singly terminate the patch to a low dynamic resistance laser diode for maximally flat modulation frequency response.

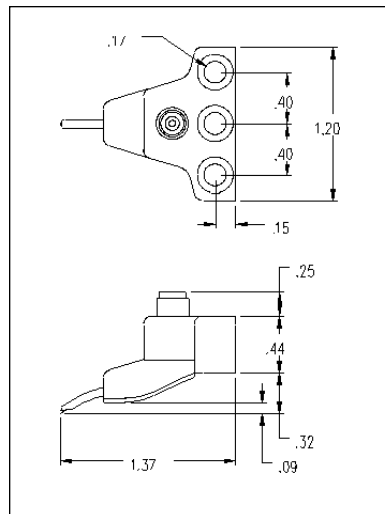


Features

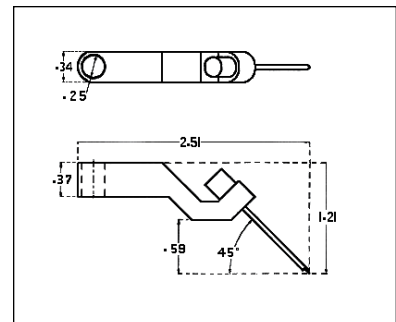
- Choice of reactive or resistive probe
- Choice of center frequency range, value and bandwidth
- Choice of probe tip impedance
- Choice of body styles, ACP or FPC

Advantages

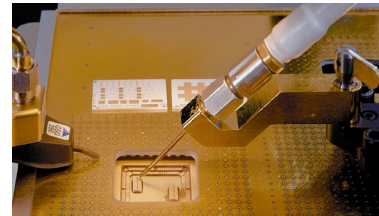
- Improved load-pull measurement tuning range
- Ability to make accurate on-wafer measurement of low-impedance power devices
- Stabilize oscillations in high-gain devices
- Impedance match to low dynamic resistance laser diodes
- Custom configured for your application



Probe style for: ACP20-Z, ACP40-Z and ACP-R



Probe style for: FPC-R



| Probe head type | Part number (Note 1, 2, 3) | Center frequency | Bandwidth (GHz) | Connector & tip type | Impedance range (Ω) | MicroChamber compatible |
|--------------------------|----------------------------|------------------|-----------------------------------|----------------------|--|-------------------------|
| Reactive Probe (Note 4) | ACP20-Z-GSG-xxx | 0.85 to 20 GHz | < 10% Std. 10% to 20% optional | BeCu 2.92 mm (f) | 24 to 50 Std. 10 to 24 optional | Yes |
| | ACP40-Z-GSG-xxx | 20 to 40 GHz | | | | |
| Resistive Probe (Note 4) | ACP-R-GS-xxx | | 0 to 10 | BeCu 2.92 mm (f) | 45 \pm 5% Std. 10 to 300 optional | Yes |
| | ACP-R-SG-xxx | | | | | |
| | ACP-R-GSG-xxx | | | | | |
| Resistive Probe (Note 4) | FPC-R-GS-xxx | | 0 to 10 | BeCu 2.92 mm (f) | 45 \pm 5% Std. 10 to 300 optional | No |
| | FPC-R-SG-xxx | | | | | |
| | FPC-R-GSG-xxx | | | | | |

Recommended cable: 132-420 for Summit 11K/12K, and S300 probe stations; 101-162-B for M150, RF-1 and 9K non-MicroChamber stations

Notes:

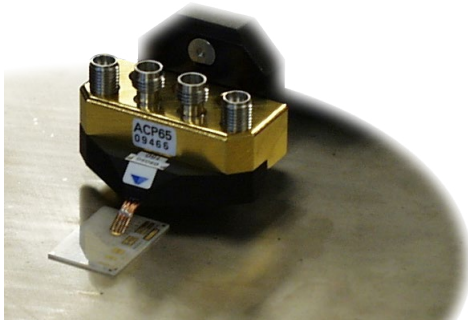
1. The -xxx suffix indicates probe contact center-to-center spacing (pitch) in microns, e.g. ACP40-Z-GSG-150 is 150 μ m (5.91 mils). Contacts are on a constant pitch and width is approximately 50 μ m.

2. The convention for describing probe head footprints is the sequence of contacts as seen looking down on the probe head tip in its functional position, with the tip pointing away from the viewer, describing contacts from left to right.

3. ACP pitches are available from 50 μ m to 1250 μ m.

4. Use Impedance Matching Probe Order Form to specify center frequency, tip impedance, bandwidth, resistance value and pitch.

SPECIAL PURPOSE PROBES



40/80 Gb/s High-Performance Quadrant Probe

Designed to provide wide bandwidth RF connections and simultaneous resonant free power bypass connections for the special needs of high-speed mixed-mode IC for optical networks.

- Low RF loss and excellent impedance control over very wide bandwidth
- High performance resonance-free bypass for low impedance power supplies
- Allows on-wafer evaluation of high performance digital circuits
- Minimal distortion of high-speed digital signals
- Maximized eye diagram test performance at wafer test
- Durable Air Coplanar tip technology for long contact life



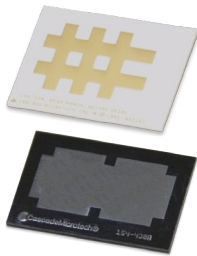
Cryogenic Probe

Designed to provide superior mechanical properties at cryogenic temperatures while maintaining solid RF measurement performance.

- Functional temperature range of -263 to +150°C
- Stainless steel tip material for thermal decoupling
- Coaxial cable with TCE matched inner and outer conductors
- Consistent tip geometry even at cryogenic temperatures

SUPPORTING ACCESSORIES

Contact Substrate

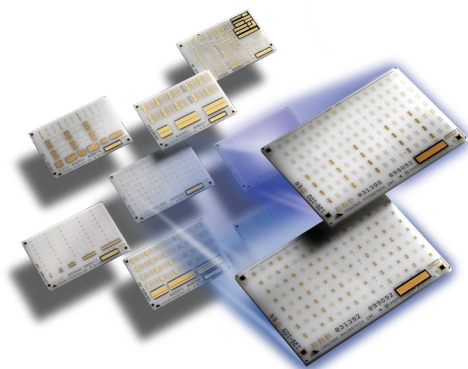


Ordering Information

| Part Number | Description |
|-------------|--|
| 005-018 | Gold on ceramic. Used for planarization of probe. |
| 154-430 | Aluminum (2 μm) on silicon. Used for planarization of probes and looking at scrub marks. |

Impedance Standard Substrate (ISS)

Cascade Microtech's family of Impedance Standard Substrates (ISS) support all of your high-frequency probing applications. Using them ensures greater accuracy and better repeatability in on-wafer calibration of vector network analyzers. Only Cascade Microtech offers the proven accuracy of LRRM calibrations with automatic load inductance compensation.



Ordering Information

| Part number | Description | Cal sites | Pitch (μm) |
|----------------------|--------------------------|---|--|
| 005-016 | General purpose | Cal sites vary | |
| 101-190 | LRM | 27 GSG | 100 to 250 |
| 103-726 | GS | 27 GS or SG | 100 to 250 |
| 104-783 | W-band | 27 GSG | 75 to 150 |
| 104-909 | Narrow pitch | 13 GSG, 7 GS, 7 SG | 50 to 150 |
| 106-682 | Wide pitch GSG | 8 GSG | 250 to 1250 |
| 106-683 | Wide pitch GS/SG | 8 GS, 8 SG | 250 to 1250 |
| 106-686 | GP membrane | 25 loads | 80 to 3000 |
| 108-010 | Very wide pitch GSG | 4 GSG | 150 to 3000 |
| 108-011 | Very wide pitch GS/SG | 4 GS, 4 SG | 150 to 3000 |
| 109-531 | Right angle | 5 N-E, 5 N-W, 5 E-W | 100 to 500 |
| 114-456 | ACP-RC | 27 GSG | 100 to 150 |
| 126-102 | Dual/Differential | 17 GSGSG, SGS, SGSG, GSGS | 150 |
| 129-239 | Dual/Differential | 17 GSGSG, SGS, SGSG, GSGS | 100 to 125 |
| 129-240 | Dual/Differential | 17 GSGSG, SGS, SGSG, GSGS | 150 to 225 |
| 129-241 | Dual/Differential | 10 GSGSG, SGS, SGSG, GSGS | 250 |
| 129-246 | Dual/Differential | 18 GSSG, SSG, GSS | 100 to 150 |
| 129-247 | Dual/Differential | 18 GSSG, SSG, GSS | 175 to 250 |
| 129-248 ¹ | General purpose thru | Qty four each, straight, cross, loop back thrus | GSGSG (300 to 650) GSSG (300 to 950) |
| 129-249 ¹ | General purpose thru | Qty four each, straight, cross, loop back thrus | GSGSG (700 to 1250) ² GSSG (1000 to 1250) ² |
| 138-356 | Waveguide Infinity Probe | 15 GSG for 50 μm 15 GSG for 75 μm | GSG 50 to 75 |
| 138-357 | Waveguide Infinity Probe | 9 GSG for 100 μm 9 GSG for 125 μm 12 GSG for 150 μm | GSG 100 to 150 |

1. Requires P/N 106-683 or P/N 129-249 for wide pitch differential/multiport applications
2. Qty 2 each for pitches 1000-1250 μm

Calibration Substrates for T-Wave Probes

| Part number | Description | Pitch (μm) |
|-------------|--------------------------------------|------------|
| 165-731 | T-Wave Probe, 750 - 1100 GHz, WR 1.0 | 25 |
| 165-734 | T-Wave Probe, 500 - 750 GHz, WR 1.5 | 25 |
| 165-735 | T-Wave Probe, 325 - 500 GHz, WR 2.2 | 25 |
| 165-736 | T-Wave Probe, 325 - 500 GHz, WR 2.2 | 50 |
| 165-737 | T-Wave Probe, 220 - 330 GHz, WR 3.4 | 25 |
| 165-738 | T-Wave Probe, 220 - 330 GHz, WR 3.4 | 50 |
| 165-739 | T-Wave Probe, 220 - 330 GHz, WR 3.4 | 75 |
| 165-740 | T-Wave Probe, 220 - 330 GHz, WR 3.4 | 100 |
| 165-741 | T-Wave Probe, 170 - 260 GHz, WR 4.3 | 25 |
| 165-742 | T-Wave Probe, 170 - 260 GHz, WR 4.3 | 50 |
| 165-743 | T-Wave Probe, 170 - 260 GHz, WR 4.3 | 75 |
| 165-744 | T-Wave Probe, 170 - 260 GHz, WR 4.3 | 100 |
| 165-745 | T-Wave Probe, 140 - 220 GHz, WR 5.1 | 25 |
| 165-746 | T-Wave Probe, 140 - 220 GHz, WR 5.1 | 50 |
| 165-747 | T-Wave Probe, 140 - 220 GHz, WR 5.1 | 75 |
| 165-748 | T-Wave Probe, 140 - 220 GHz, WR 5.1 | 100 |

SUPPORTING ACCESSORIES

Calibration Standard (CSR)

The CSR family of calibration substrates is compatible with the |Z| Probes. All CSR calibration substrates include the Open standard on the substrate itself, providing a more accurate calibration when compared to simply lifting the probes for Open. Also, the resistance of the Load standard remains stable within 0.3% of the ideal value (50 Ω), over a temperature range from 10 to 430 K.

Ordering Information

| Part number | Description | Pitch (μm) |
|-------------|--|--------------|
| 41702 | Z Probe, CSR-4, GSG | 250 to 500 |
| 41704 | Z Probe, CSR-5, GS/SG | 250 to 500 |
| 56407 | Z Probe, CSR-6, GS/SG | 50 to 250 |
| 62025 | Z Probe, CSR-8, GSG | 100 to 250 |
| 73319 | Z Probe, CSR-9, GSG | 50 to 150 |
| 62563 | Z Probe, CSR-15, GSG | 500 to 1250 |
| 69061 | Z Probe, CSR-16, GS/SG | 500 to 1250 |
| 71391 | Z Probe, CSR-17, GSG | 1000 to 2500 |
| 67074 | Z Probe, CSR-18, GS/SG | 1000 to 2500 |
| 51077 | Z Probe, CSR-30, GSGSG | 100 |
| 51078 | Z Probe, CSR-31, GSGSG | 150 |
| 51079 | Z Probe, CSR-32, GSGSG | 200 |
| 51080 | Z Probe, CSR-33, GSGSG | 250 |
| 51081 | Z Probe, CSR-34, GSGSG | 500 |
| 51082 | Z Probe, CSR-35, GSGSG | 125 |
| 51874 | Z Probe, CSR-41, GSSG | 125 to 150 |
| 51875 | Z Probe, CSR-43, GSSG | 200 to 250 |
| 51876 | Z Probe, CSR-44, GSSG | 400 to 600 |
| 52379 | Z Probe, CSR-40, GSSG | 100 |
| 53527 | Z Probe, CSR-50, SGS | 100 |
| 53528 | Z Probe, CSR-51, SGS | 125 to 150 |
| 53529 | Z Probe, CSR-53, SGS | 200 to 250 |
| 53530 | Z Probe, CSR-54, SGS | 400 to 500 |
| 71392 | Z Probe, CSR-101, GSG/GS/SG | 100 to 300 |
| 136643 | Z Probe, Calibration substrate in a silicon wafer | |

Cables

Cascade Microtech's range of low-loss, thermally-stable cables ensure higher-quality measurements and longer-lasting calibrations. Each cable has a male connector at one end that connects to the probe and a female connector at the other end to connect to the test instrumentation. For vertical style probes, the male connector includes an integrated 90° elbow.

Cables for Use with Infinity and ACP Probes

| Freq (GHz) | Probe station | Body style | Length (inch) | Part number |
|------------|--------------------------------|------------|---------------|-------------|
| DC to 40 | Summit 11K/12K, S300 | A | 48 inch | 132-423 |
| | | V | 48 inch | 132-420 |
| | M150, RF-1,9K, no MicroChamber | A | 48 inch | 124-084-B |
| | | V | 48 inch | 101-162-B |
| DC to 50 | Summit 11K/12K, S300 | A | 48 inch | 132-424 |
| | | V | 48 inch | 132-421 |
| | M150, RF-1,9K, no MicroChamber | A | 48 inch | 124-085-B |
| | | V | 48 inch | 103-202-B |
| DC to 67 | Summit 11K/12K, S300 | A | 36 inch | 132-425 |
| | | V | 36 inch | 133-422 |
| | M150, RF-1,9K, no MicroChamber | A | 36 inch | 124-606-B |
| | | V | 36 inch | 124-605-B |
| DC to 110 | Summit 11K/12K, S300 | A, V | 18 cm | 132-458 |
| | Elite300 | A, V | 24 cm | 147-316 |

'A' denotes 45° angled coaxial connector body style.

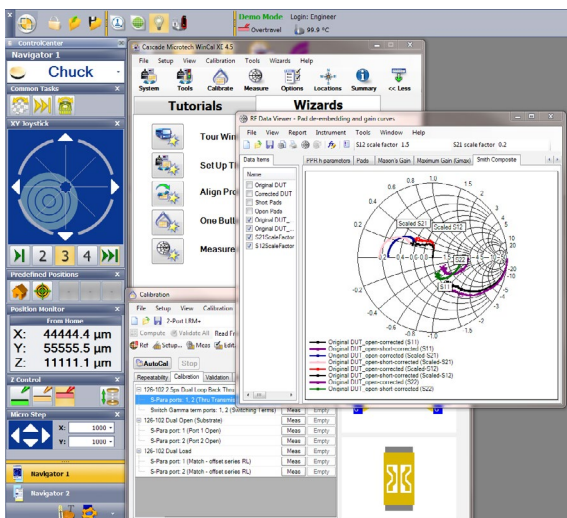
'V' denotes vertical coaxial connector body style.

For Waveguide sections consult factory.

SUPPORTING SOFTWARE

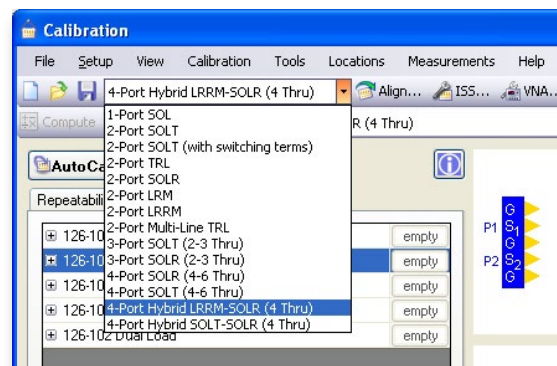
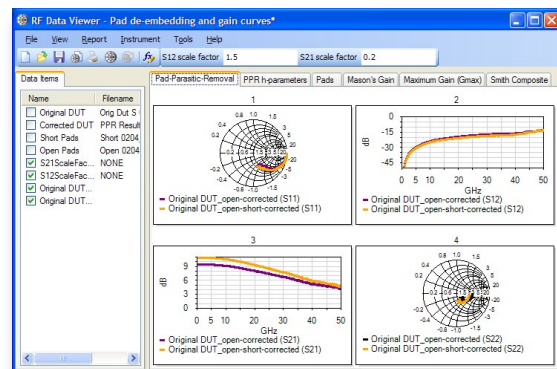
Accurate on-wafer S-parameter measurements up to 500 GHz and beyond

The WinCalXE software accurately calibrates the measurement system and automates measurements, data collection and data transformation, providing repeatable and precise S-parameter data. The WinCal XE 4.6.2 version is fully compatible with |Z| Probe, ACP probe and Infinity Probe families and supports both ISS and CSR calibration substrates. It is also compatible with Velox™, ProberBench™ and Nucleus™ probe station software, and most commercially available Vector Network Analyzers.



Advanced capability for both present and the future

WinCal XE easily converts S-parameters to a device appropriate format, and also enables immediate and live data reduction and viewing. WinCal XE also provides the broadest range of VNA calibration choices up to 4 ports.



Easy, fast, and accurate RF measurement

WinCal XE's guided and smart system setup and customizable Wizards ensure a correct system setup, reliable VNA calibration, and repeatable data.

Key Features:

- Automatic VNA calibration using calibration method of your choice
- Extensive guidance for correct system setup and calibration
- Convert S-parameters to a device appropriate format
- Customizable display templates and Wizards that adapt to your need
- Powerful measurement sequencing capabilities
- LRRM-SOLR hybrid 4-port calibrations for precision 4-port calibrations
- Error Set Manager provides error set augmentation and error set comparison tools
- Multi-line TRL cal to compare your preferred calibration methods to a NIST-style calibration

Ordering information:

| Part number | Description |
|-------------|--|
| 142-171 | WinCal XE, full version (USB) |
| 142-173 | WinCal XE, 30-day demo (USB) |
| 142-178 | WinCal XE, field upgrade (from demo to full version) |
| 153-950 | WinCal XE, university version |
| 153-952 | WinCal XE, field upgrade from earlier versions |

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